

1991

An automated non-destructive test system

Connie Lee Lohr Bishop
University of Dayton

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AN AUTOMATED NON-DESTRUCTIVE TEST SYSTEM

Thesis

Submitted to

Graduate Engineering & Research
School of Engineering

UNIVERSITY OF DAYTON

In Partial Fulfillment of the Requirements for

The Degree

Master of Science in Electrical Engineering

by

Connie Lohr Bishop

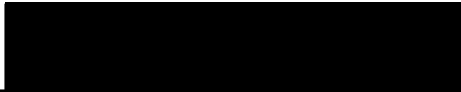
UNIVERSITY OF DAYTON

Dayton, Ohio


April 1991

AN AUTOMATED NON-DESTRUCTIVE TEST SYSTEM

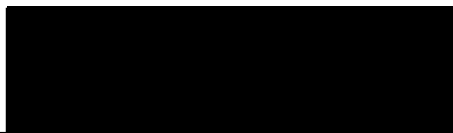
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ABSTRACT

AN AUTOMATED NON-DESTRUCTIVE TEST SYSTEM

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University of Dayton, 1991

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The Automated Non-destructive Test System (ANTS) was specifically designed to test a transducer at EG&G Mound Applied Technologies. The tests consist of verifying that the circuits are wired correctly and that critical faults do not exist. The proper function and safety of this device require that every unit built pass these tests or be rejected.

This paper will describe the hardware and software design criteria and how they were implemented in the fabrication and operation of the test system. The test system consists of commercial equipment integrated with custom designed hardware. A Hewlett Packard computer automates the system by interfacing controlling software with the hardware. A software program written to control the function and the timing of the tests also provides a means for data acquisition.

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ACKNOWLEDGMENTS

I would like to thank those who supported me on this project. Especially Leander Hall for fabricating the test system; my supervisor Keith Ohler and my department manager J. Fred Madden.

A special thank-you must go to my husband Todd for giving me the encouragement and understanding I needed.

CHAPTER I

INTRODUCTION

The reliability of components produced by the weapons industry is essential. There are few businesses where the survival of so many, the defense of a nation, depends as heavily on the proper function of its product. Non-destructive testing is a means by which a device can be analyzed without impairing its functional qualities. The results of these tests determine whether the device is acceptable and can be used in the next stage of assembly.

EG&G Mound Applied Technologies (The Mound), located in Miamisburg, Ohio, is a Department of Energy (DOE) installation. The Mound is a production facility of weapon system components. In addition to production, non-destructive and destructive testing of these components is also performed at this site. The scope of this paper will describe in detail the Automated Non-destructive Test System (ANTS) designed to perform various tests on a transducer that is part of a system sub-assembly.

The Automated Non-destructive Test System is designed to verify critical wiring in the transducer. Accurate measurements and assessments must be made for several different circuits in the unit to be assured of transducer reliability. For safety and operational purposes, ANTS is

also required to verify that there is sufficient insulation so that no arcing will occur between the circuitry and the case of the transducer when exposed to an input signal. This is done for nine different test points. The system incorporates a computer to control the function, timing, order, and assessment of these tests.

The controlling computer controls and interrogates other equipment via a parallel bus. Custom designed hardware in the test system is interfaced by general purpose input/output cards in the computer. Test results are first stored in memory and then transferred to storage on a floppy disk. The data is electronically transmitted to Sandia National Laboratories where it is archived. Numerous software routines execute the various test and data storage sequences. User friendly operator interface routines expedite the testing procedure since a large number of transducers are tested by the test system.

Connecting to the test sample requires special fixturing that must be durable, reliable, and reusable. The design of the fixture ensures that adequate electrical contacts for testing are made without damaging the connectors on the unit.

Since the test results can be only as good as the system that produces the results, the validity of ANTS must be verified. Calibration of the equipment and electronics in the system is performed and documented on a periodic basis. This was taken into consideration in the hardware design of the system. Separate from the testing software,

calibration software was written to aid in this task. In addition to periodic calibrations, simulators were designed to be used with the system. These simulators emulate the test component and are used to verify that the test system is functioning properly. The simulators are calibrated as part of the test system and then used by the operator at the beginning and the end of every test session.

These are the considerations that were taken into account when designing the non-destructive tester. Design considerations and decisions for fabrication and operation of ANTS will be described in the following chapters.

CHAPTER II

TRANSDUCER OVERVIEW

The transducer which the Automated Non-destructive Test System is designed to test is based on transformer technology. Figure 2.1 is a simplified diagram of the device. It is a transformer with a primary winding and a secondary winding.

On one leg of the secondary winding is a Current Viewing Transformer (CVT). This device is a means of monitoring the function of the transducer during destructive testing. The current is calculated from the voltage produced by the induced electromotive force (emf). The emf is the number of turns in the coil times the derivative of the magnetic flux with respect to time.¹

$$\text{emf} = N d\phi / dt$$

The calculated current is based on parameters supplied by the manufacturer of the CVTs. This current signal is analyzed to determine if the transducer functioned properly. The Current Viewing Transformers are critical in

¹W. H. Hayt, Jr., Engineering Electromagnetics (New York: McGraw-Hill, 1981), p. 347.

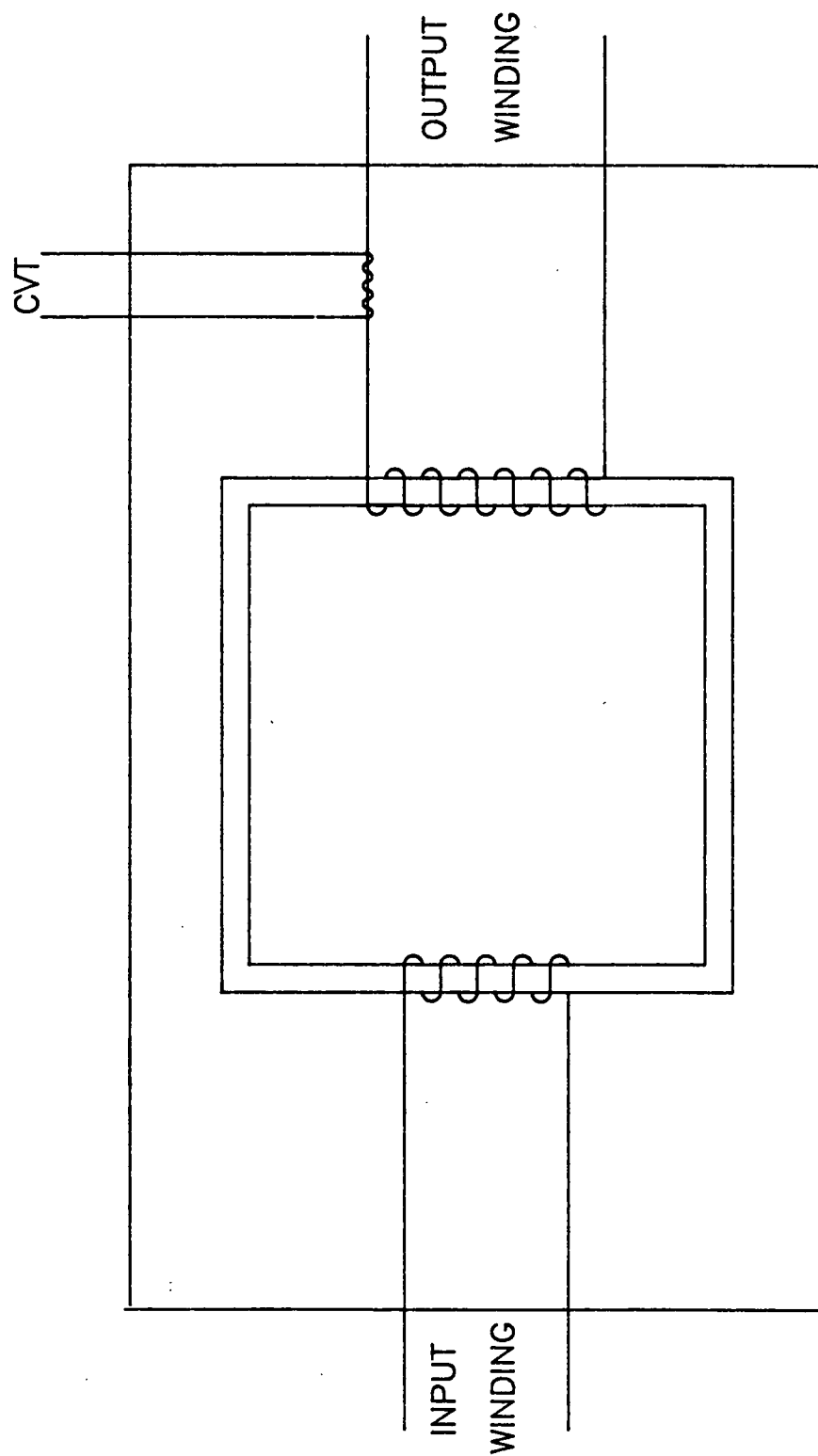


FIGURE 2.1: TRANSDUCER

predicting the performance of an entire production lot. For this reason, the CVTs are 100 percent non-destructively tested on ANTS for proper static parameters.

The transducer also contains an explosive device that has input leads which are not shown in Figure 2.1. These leads must be electrically measured for safety reasons. If there is a fault in this circuit, the unit could malfunction.

Additional non-destructive type tests are performed to determine the stability and electrical isolation of the case. The entire device is packaged in a metal case.

Function

The transducer functions when a direct current is applied to the primary, or input, winding of the transformer. This current produces a steady magnetic field. By the integral form of the Biot-Savart Law the magnetic field intensity H is the sum of the differential current elements, Idl , over a closed surface.

$$H = \int ((Idl \times a_R) / (4\pi R^2))$$

where the cross product with a_R defines the direction of the field and R is the distance from the differential current element to the surface of the magnetic field.²

²Ibid., p240.

The core of the transformer becomes saturated with magnetic flux lines ϕ . Magnetic flux is defined by

$$\phi = \int B ds$$

where B is the magnetic flux density which is the product of the magnetic field intensity and the permeability μ of the material of the core.³

$$B = \mu H$$

Once a steady magnetic field is established, the explosive device is initiated by an external signal which is not related to the primary or the secondary windings. The resulting explosion causes the established magnetic field to collapse. This produces a sudden change in the magnetic flux which causes an induced current in the secondary, or as it will be referred to from now on, the output winding. The timing sequence is critical since the signal from the output winding must reach its destination before the circuit is destroyed. The abrupt burst of current in the output winding of the transformer is the desired end of the transducer's function.

³Ibid., p319.

Tests

The non-destructive tests that ANTS performs on this transducer reinforces the reliability of the components that go into the weapon system. As described above, the proper function of the transformer type circuit is critical.

The first set of parameters that ANTS tests is the resistance of all the coils in the unit. This consists of connecting to six different points on the transducer and taking three measurements. The resistance readings are automated by the controller which interfaces to a digital ohmmeter in the system. The technique by which these resistance values are obtained is known as a four wire resistance measurement and results in negligible error due to the test leads. In resistance readings below ten ohms, the resistance of the test leads can significantly contribute to the measurements which would result in erroneous data. This is a factor which must be taken into consideration since the resistance of the coils fall within this range.

This resistance is used primarily to verify that the number of turns in each coil meet the required specification. Since the resistance is a function of the length of the wire in the coil, the number of turns in the coil defines the length, therefore specifying the required resistance:

$$R=L/\sigma S$$

where σ is the conductivity of the material, S is the cross-sectional area and L is the length of the wire.⁴ Since the output current is dependent on the number of turns in the coil as described earlier, a faulty winding in the transformer could result in a device that would not function properly. The resistance of the Current Viewing Transformer is also verified since the proper calculation of current is needed to correctly indicate the function of the transducer during destructive testing. A resistance reading out of range could also indicate other types of faults in the circuit. Whenever a resistance falls out of range, the unit is rejected and is analyzed to determine the cause of improper function.

The next type of test to be addressed is referred to as Insulation Resistance (I.R.). This is executed by applying a high voltage across two terminals and verifying that the current flow, known as the leakage current, is a minimal value. This will ensure that this circuit is characterized by a very high resistance. A test of this nature provides concrete data to verify that these points are electrically isolated.

There are nine of these tests performed. Three of them are accomplished by applying high voltage across one terminal of each coil and the case of the transducer. This

⁴Ibid., p.136.

includes the input and the output windings and the CVT. The next test is the application of the high voltage across an input signal lead to the explosive device and the case of the transducer. The remaining five tests consist of applying the high voltage across other points that must be verified to be electrically isolated. These other points are not described in this paper for security reasons. However, they are mentioned here since ANTS performs these tests. Each of these tests is performed independently of all the others. During each application of the high voltage, a current comparator circuit in the test system is monitored by the computer. If the current is too high, the comparator circuit recognizes this and sends out a signal indicating the condition. A failure of this test implies that the points of voltage application are not sufficiently insulated from each other. This can result in an unstable device and make the operation of the transducer questionable.

The establishment of continuity and insulation resistance is a critical factor when determining the reliability of the transducer. The Automated Non-destructive Test System is a vital supporting part of the production of such units.

CHAPTER III

HARDWARE

As Figure 3.1 shows the Automated Non-destructive Test System is a single bay bench top tester. The controlling computer, printer and safety chamber are all within close proximity of the tester cabinet.

The hardware of the test system consists of both commercial equipment and custom designed circuits. The selection of purchased equipment was based on specifications of accuracy, precision and safety limits required by the transducer. Figure 3.2 is a block diagram of the test system. Integrating this equipment with the other hardware components is what gives ANTS the capability of performing the required tests as described earlier.

Equipment

There are five major pieces of commercial equipment used in ANTS to take measurements, output signals, collect and store data, and control the process. They are a Hewlett Packard Controller, a Keithley Digital Micro-Ohmmeter, a Hewlett Packard Digital Multimeter, a Hewlett Packard Disk Drive, and a Hewlett Packard Printer.

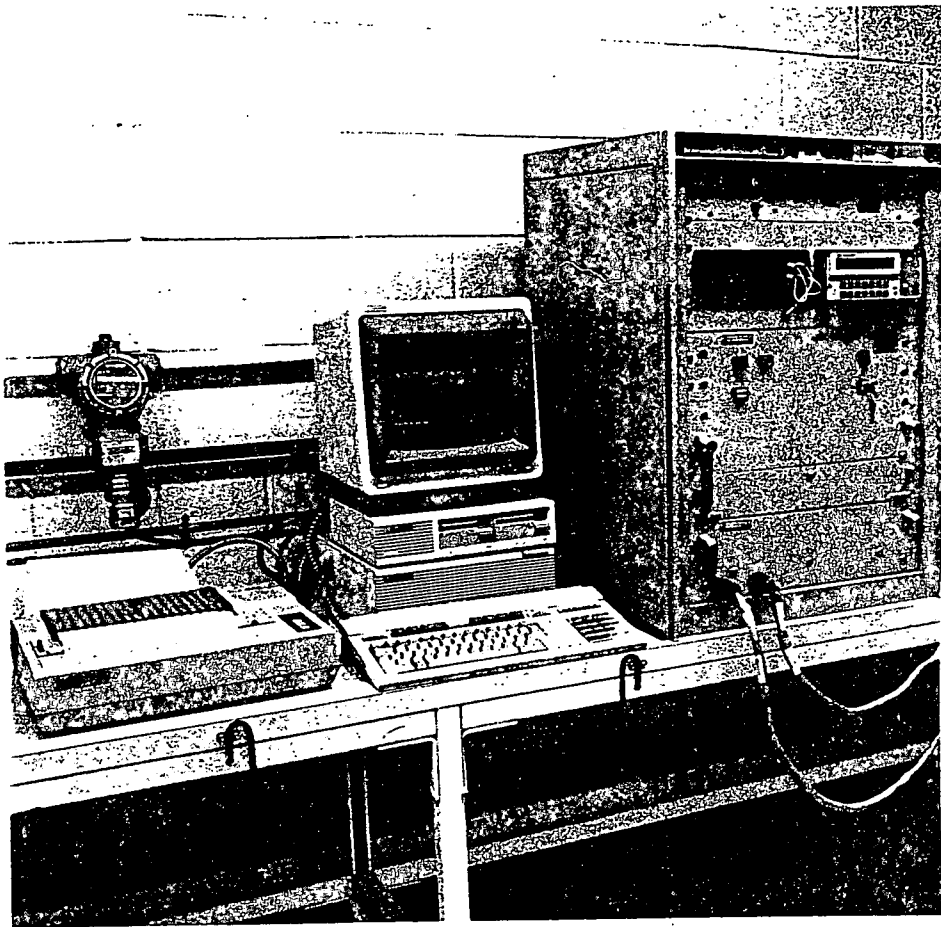


FIGURE 3.1: AUTOMATED NON-DESTRUCTIVE TEST SYSTEM

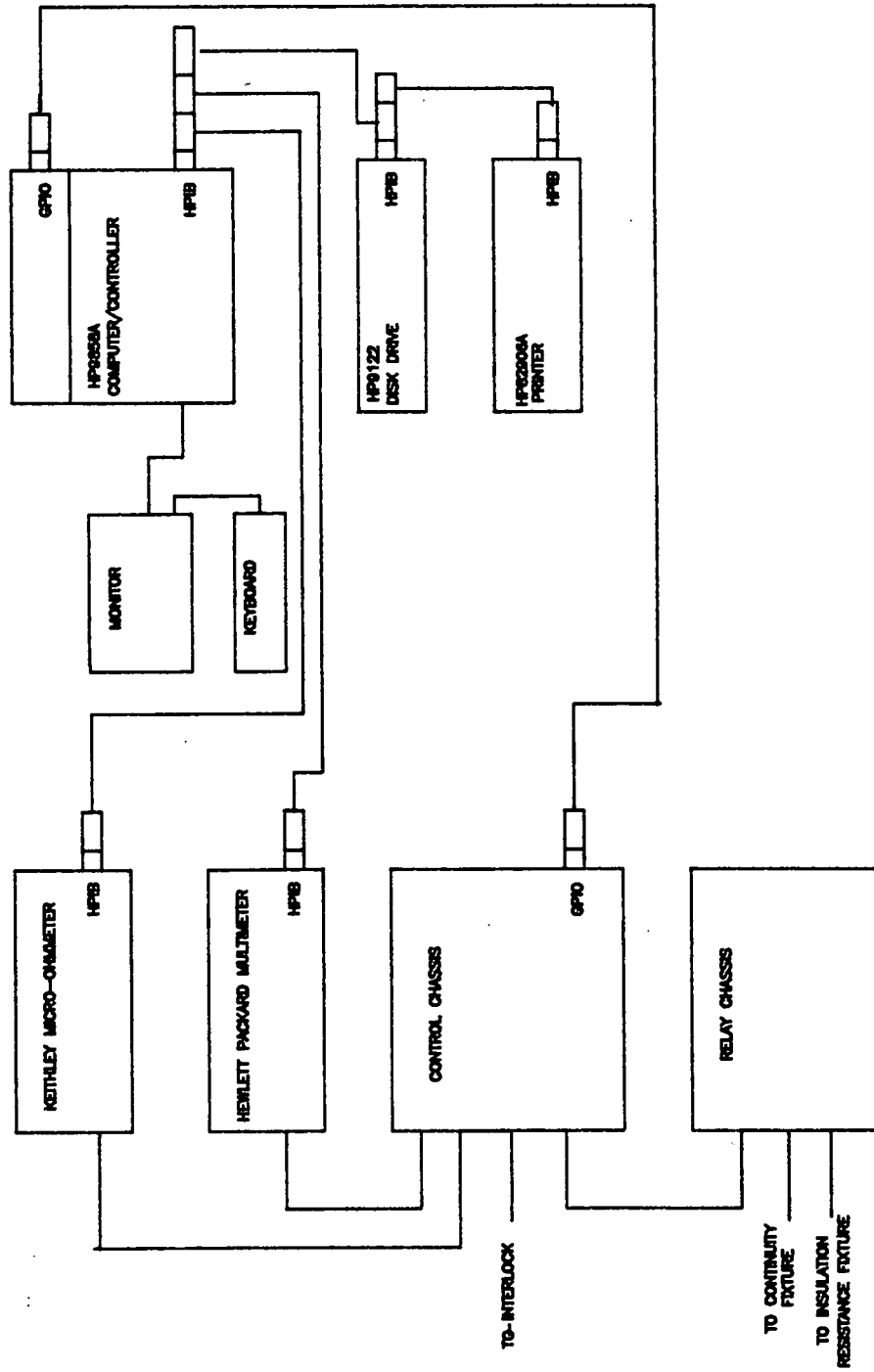


FIGURE 3.2: BLOCK DIAGRAM

Controller

The computer which controls the test system is a Hewlett Packard 9000 family 332 workstation. The Model 332 is based on a MC68030 processor and has a 16.7 megahertz clock. The processor is characterized by a 32 byte data cache and a 32 byte instruction cache. One megabyte of RAM is accessed by a 32 bit data bus and a 32 bit address bus.

The computer interfaces to other equipment via the Hewlett-Packard Interface Bus (HPIB). All electrical and timing requirements of the IEEE 488 standard parallel interface are satisfied by this bus. Each piece of equipment is assigned an address on this bus. The computer uses this addressing scheme to select a piece of equipment to listen or to talk. This address is selected by setting DIP switches on each device.

The custom designed hardware is controlled and monitored by General-Purpose Input/Output (GPIO) Interface lines of the computer. The GPIO Interface provides a 16 bit bi-directional binary data transfer technique. It has the capability of transmitting data on the output lines at the same time the computer is receiving data on the GPIO input lines. The computer system used in ANTS is configured with two sets (cards) of GPIO Interface lines. Each card has an interface select code which is selected by setting a DIP switch that provides a means for the computer to differentiate between the two.

The data on each input line is received by an exclusive OR gate on the GPIO Interface. The hardware

designed to transmit data indicating the state of various process conditions uses a double pole switch. Figure 3.3 shows this configuration. The interface requires at least three volts on its input lines to register as a binary one. A low must be indicated with no more than 0.7 volts on the input lines. As Figure 3.3 shows, five volts and ground are used to establish the desired states. Switching is accomplished by a relay or a key switch.

Each of the GPIO data-output lines is driven by an open collector buffer amplifier on the interface. This is used to drive a 4N35 optically coupled isolator in the test circuit. The isolator is used to protect the GPIO interface from electrical spikes that might be transmitted from the test circuit. Figure 3.4 shows this configuration. When a GPIO output line turns an opto isolator on, voltage is supplied to further trigger events in the testing process.

The workstation has a monochrome monitor which displays operating instructions and test results to the operator. An alpha-numeric keyboard is supplied for the user to enter test item information and to make test process selections that are displayed on the screen of the monitor.

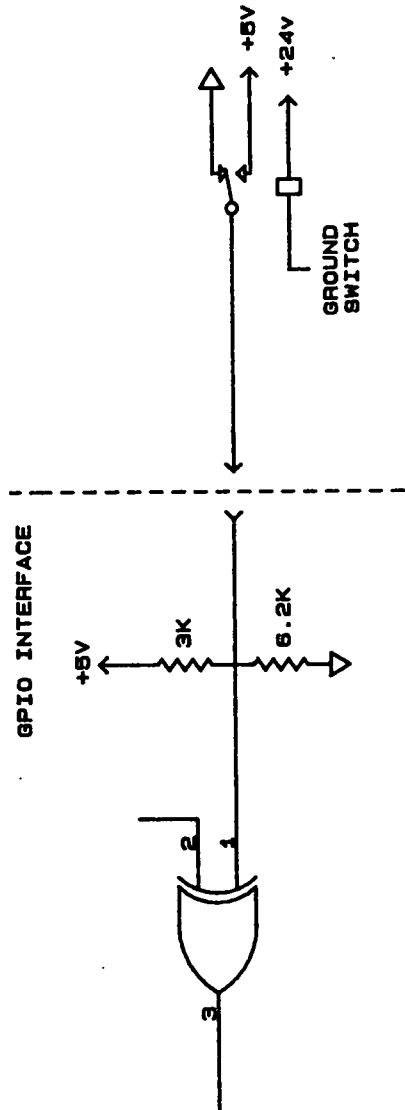


FIGURE 3.3: GPIO INPUT INTERFACE

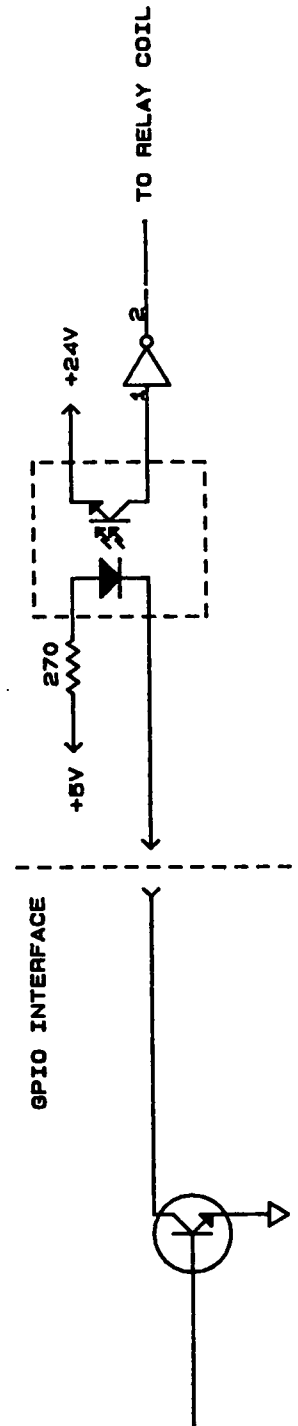


FIGURE 3.4: GPIO OUTPUT INTERFACE

Digital Micro-Ohmmeter

The first piece of commercial equipment that interfaces to the computer is a Model 580 Keithley Digital Micro-Ohmmeter. It performs the Continuity tests on the transducer by making accurate four wire resistance measurements.

This type of resistance measurement consists of supplying a known current through a resistor, or as in this case, a coil of a transformer. A source leg and a return leg for this current source comprises two of the leads in a four wire system. As the current is being supplied through the element, the voltage is measured across the coil. To make the voltage measurement, two more leads are used to attach to the device being tested. The two points at which this is accomplished is in the same proximity as the connections of the two current leads. Figure 3.5 illustrates this circuit. As a consequence no voltage induced by the current through the current leads is added to the voltage across the coil. Given the measured voltage and the known current the resistance is calculated via Ohm's Law. The current sourcing, voltage measuring and resistance calculating are all done internal to the Keithley Micro-Ohmmeter. A four wire cable connects to four terminals on the front panel of the meter and is fed back through the chassis to interface with custom designed switching circuitry.

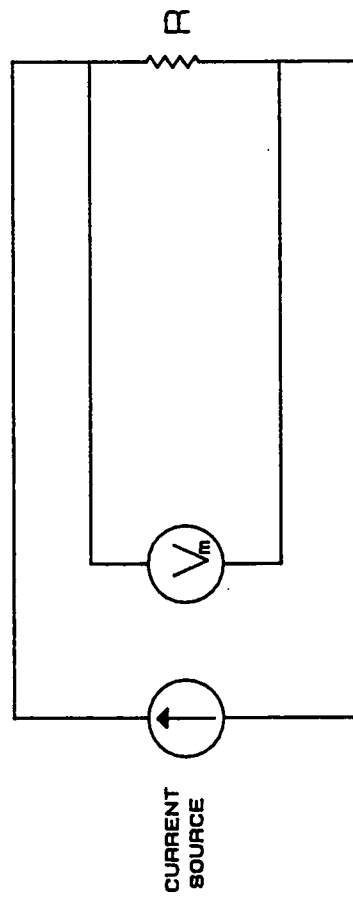


FIGURE 3.5: FOUR WIRE RESISTANCE MEASUREMENT

The computer sends instructions over the HP-IB interface bus to the meter to set it up to take resistance measurements. When a test is performed, the necessary switching is done to make the required connections between the micro-ohmmeter and the device under test. The result of a test of this nature is a resistance reading which is placed in a temporary memory at the address of the meter. The software controls the timing of the switching and addresses the micro-ohmmeter at the appropriate time to send this data back over the bus to the computer.

Digital Multimeter

A Hewlett Packard Model 3478A Digital Multimeter is used to verify the voltage output of the high voltage power supplies while performing the Insulation Resistance tests. A cable from the terminals on the rear panel of the meter connects the meter across a 1000:1 voltage divider network. This divider network is switched between each of the outputs of the two high voltage power supplies. The computer sends instructions over the HP-IB bus to the meter to take the voltage readings. After these values are obtained, they are transmitted to the computer over the same bus.

The HP3478A has the capability of making a four wire resistance measurement. However, the stability and accuracy of the device is insufficient in the resistance range where the Continuity tests are performed. The

initial plan to switch this meter between the two functions, resistance and voltage, for the two types of tests was discarded.

Storage Devices

A Hewlett Packard HP9122 dual disk drive is the source for program and data storage. A floppy disk with the operation or calibration program is inserted into one of the drives, specifically drive 0. There is an operation and a calibration procedure that instructs the operator to do this before turning on the test system. Even though the program is loaded into memory, the disk remains in that drive during operation. In the second drive, drive 1, a blank disk is used to store the test results.

In addition to storing the data on a disk, a print out is generated for each unit tested. A Hewlett Packard HP82906A printer is used for this purpose.

Control Chassis

The control chassis consists of two high voltage power supplies, two comparator circuits, and hardware designed to interface these to the Hewlett Packard computer. A special circuit designed for safety purposes is also incorporated into this chassis. This extra safety feature is required because of the explosives used in the transducer.

Power Supplies

There are two Venus high voltage power supplies to accommodate two different voltage level requirements. The first of the nine Insulation Resistance tests requires A +/-C volts be applied at the terminals to be tested. The remaining eight I.R. tests need B +/-D volts. A and B are defined as two different high voltage levels and C and D are respectively the associated tolerances. It follows that one of the high voltage power supplies is set at A volts while the other is set at B volts. This is verified during calibration of the tester. The tolerances are given to allow for drift that may occur between calibrations. The voltages are regulated by means of a screwdriver adjustable potentiometer which is remotely placed behind a calibration door on the front bottom of the control chassis. Figure 3.6 shows the front panel layout with the position of these terminals.

A 24 volt D.C. source is used to power the Venus Power Supplies. A single-pole-double-throw relay determines which high voltage power supply is to be turned on. In the de-energized state of this relay the B volt power supply is selected. If the computer, via its GPIO interface, energizes this relay then the A volt power supply is chosen. Corresponding to this relay state, a double-pole-double-throw high voltage relay connected to the output of each power supply determines which voltage will be applied to the device being tested. After all of

FIGURE 3.6: CONTROL CHASSIS FRONT PANEL

the necessary relay contacts between the output of the selected high voltage power supply and the unit under test have been activated, another relay is used to supply the 24 volt input to the selected high voltage power supply. The voltage level at the unit will change to its required value as a ramp function. The slope of the ramp is based on the internal rise time of the Venus power supply. If the high voltage was turned on before making the desired contacts through the relays the result would be the switching of high voltage. This step type behavior must be avoided to prevent possible damage to the hardware. A sudden change in current would also be detected by the comparator circuit. As will be described later, this would result in the power supply being shut down and the unit being recognized as a reject.

Comparator Circuit

In order for the Automated Non-destructive Test System to perform the Insulation Resistance tests, a method of detecting a condition that does not provide isolation is necessary. Two comparator circuits are used to accomplish this task. The circuits are identical except for being biased with different parameters for the two high voltage requirements of A volts and B volts. The comparators are best described in two stages, an input stage and an output stage.

Depending on which high voltage power supply is being used, a relay switches the corresponding comparator circuit into the test circuit. The input of this circuit is placed in series of the return leg of the selected high voltage test circuit. The input stage is shown in Figure 3.7. This configuration allows the leakage current to flow through a resistor connected in series with a pair of parallel connected back-to-back diodes. The leakage current is the small amount of current that trickles out of the unit under test when the high voltage is applied across the high resistance of the isolated points of the transducer. Ideally, these isolated points should be an open circuit with no current flow. The actual value specified for the Insulation Resistance tests is a resistance greater than ten megohms. Knowing the voltage applied across the device under test and the minimum resistance for a unit to be considered acceptable, the maximum leakage current is defined. For the A volts that current is aa.a microamps and for the B volt supply the maximum current is bb.b microamps. The variables aa.a and bb.b are used to represent these currents. The voltage produced by the maximum allowable leakage current flowing through a resistance in the input stage sets the reference voltage for the comparator. This resistance is actually a potentiometer with its adjust terminal behind the calibration door (Figure 3.6). It is set so that when the leakage current causes the voltage to exceed the set point a pulse is sent to the second stage of the comparator.

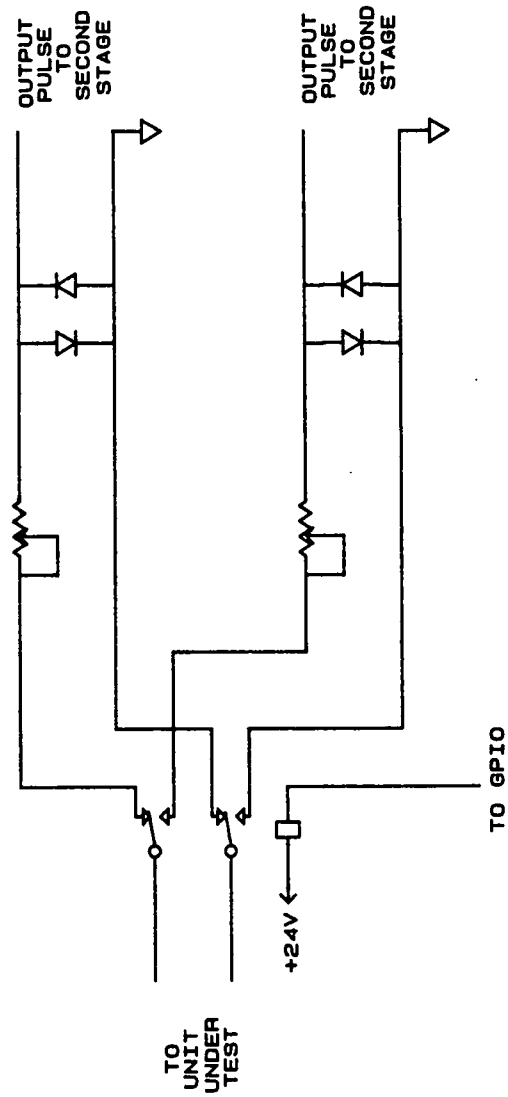


FIGURE 3.7: COMPARATOR INPUT

This will occur when the isolation resistance is too low, thus indicating a defective unit.

The input of this circuit is very sensitive to sudden changes in voltage. This is why the high voltage is ramped up to the desired value instead of being applied as a step function.

A silicon controlled rectifier(SCR) is the main element in the second stage of the comparator shown in Figure 3.8. When the gate of the SCR is triggered by the pulse generated by the first stage, the device starts to conduct, thus providing a path to ground. This ground completes a circuit needed to energize a relay and power a lamp which indicates a reject. When this relay is turned on, the path that supplies the power to the coil of the high voltage relay is broken. This eliminates the high voltage to the unit being tested. For safety reasons high voltage should be removed from a unit that has displayed characteristics of low resistance during an Insulation Resistance test. Another set of contacts on this relay is used to flag an input line on the GPIO to communicate to the computer what has happened. The software then handles this information.

Before the testing process can continue, the comparator circuit needs to be reset. This is accomplished by turning off the SCR. A momentary push button switch is placed in parallel with the anode and cathode of the silicon controlled rectifier. As Figure 3.6 shows, this push button is accessible from the front of the control

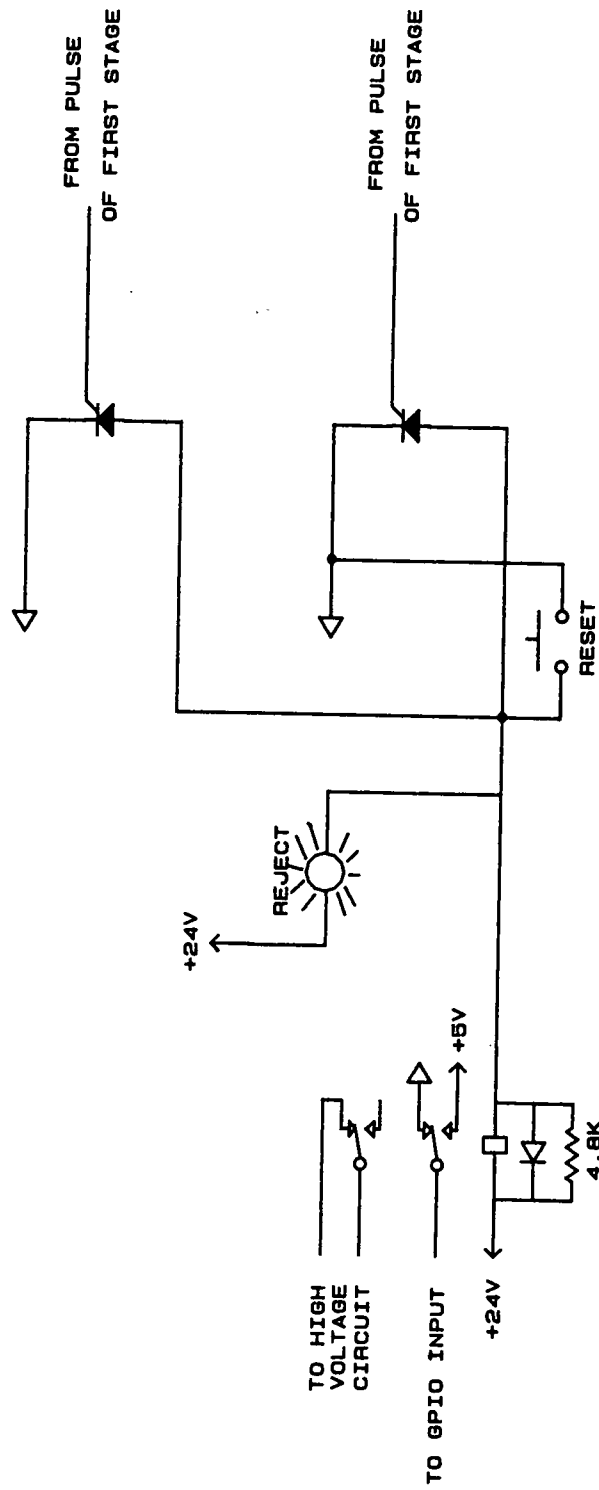


FIGURE 3.8: COMPARATOR OUTPUT

chassis. When this switch is closed a path is created which will shunt the current to ground. The moment the switch is closed, the SCR turns off. Since the high voltage has been removed there is no possible stimulus coming from the first stage to trigger the gate of the SCR at this time. After the switch unlatches there is no conducting path between the anode and cathode. Thus resetting of the comparator circuit is complete.

Control Hardware

The General-Purpose Input/Output Interface controls the testing processes by interfacing to various relays. Relays were chosen over other switching devices because of their low contact resistance.

One side of the coil of each relay is supplied with 24 volts. The relay is energized when the other side of the coil is pulled to ground. This is done via an output line on the GPIO Interface. As mentioned earlier, output lines on the GPIO are used to drive 4N35 Opto Isolators. The output of an isolator provides a path to ground when the input is driven by a GPIO line. Each relay is assigned to a GPIO output line that controls it. The software addresses the required GPIO lines for the desired process.

One set of relays is designed to make the three Continuity tests. Since these three tests have no points in common, a four-pole-double-throw relay is used to connect the Keithley Ohmmeter to a selected test. Three of these relays provide an automated method for switching the

four leads of the ohmmeter to the test points. The normally closed contacts of these relays are tied to ground. This insures that the points under test are isolated from all others. Figure 3.9 illustrates this configuration. The resistance reading obtained over the HPIB parallel bus is correlated with the selected relay and is stored by the computer for the associated test.

To perform an Insulation Resistance test, one of the two high voltage power supplies is selected as described earlier. Two test points are then selected to have the high voltage applied across. This is accomplished by closing two of the relays labeled as K202 through K209 in Figure 3.10. One of each selected relay switches its corresponding test point to the ground side of the selected high voltage power supply. The other relay switches its test point to the high side of the same selected high voltage power supply. Since two of the test points are required for more than one test, an additional relay, K201 in Figure 3.10, is used to switch the two corresponding relays, K202 and K203, between the high and the ground side of the power supply. The normally closed contact of the relays that connect to the unit are tied to ground. In addition to insulating the test points, it provides a safety feature by isolating the high voltage leads from the connectors on the exterior of the tester.

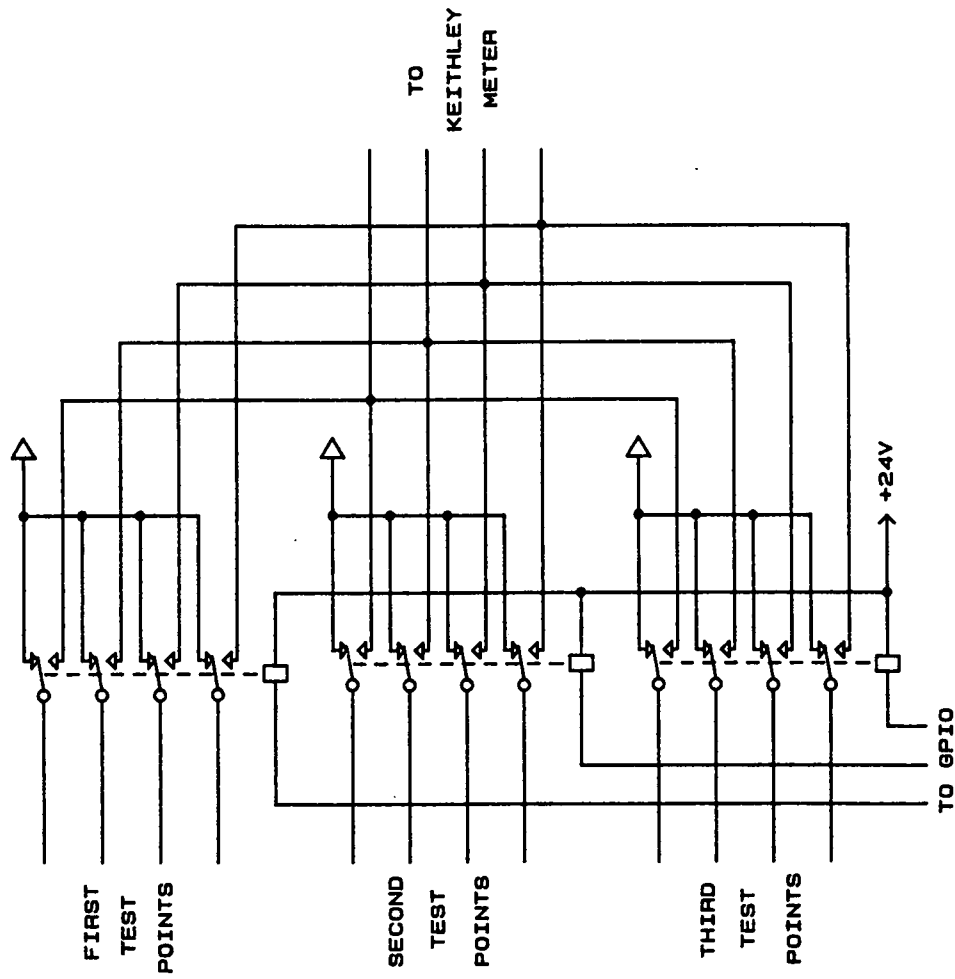


FIGURE 3.9: CONTINUITY TESTS RELAY CONFIGURATION

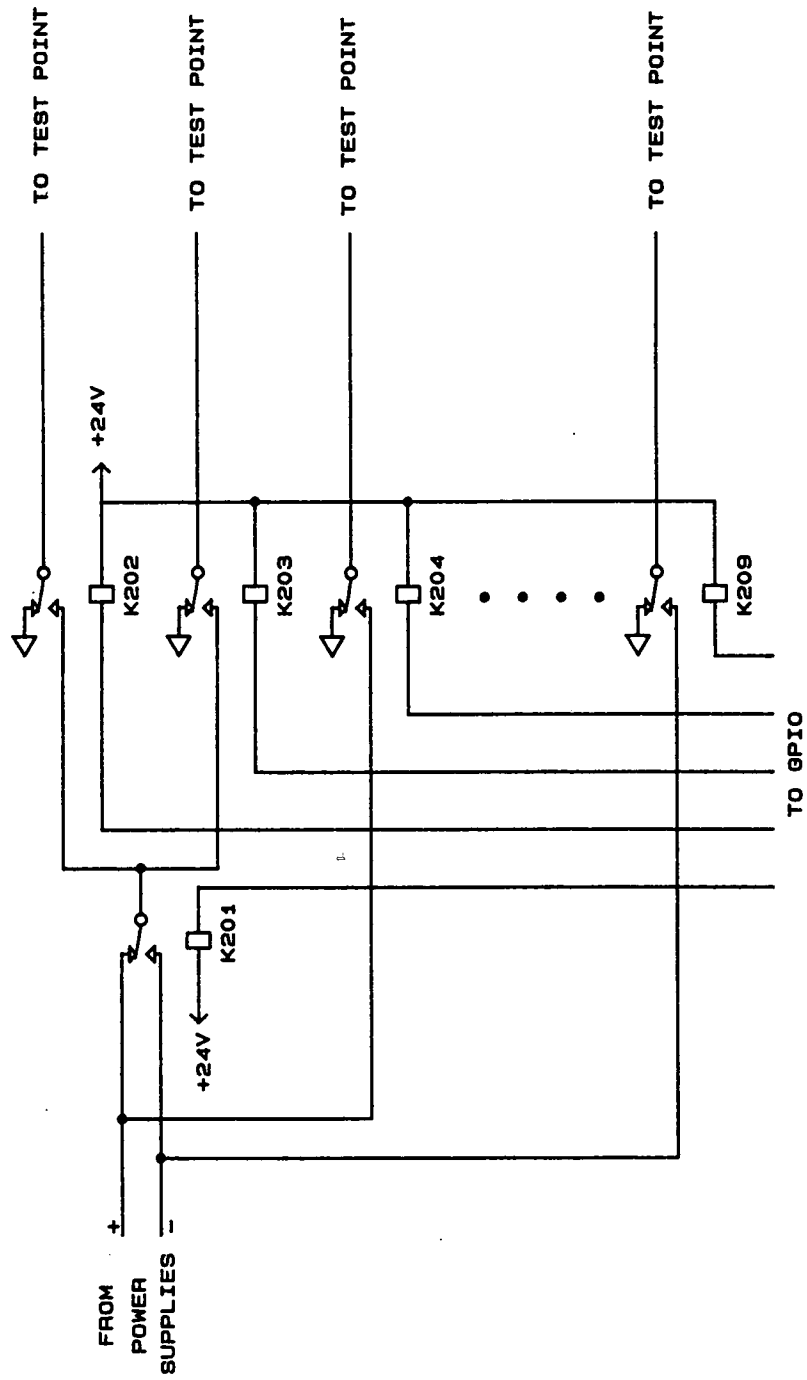


FIGURE 3.10: INSULATION RESISTANCE TESTS
RELAY CONFIGURATION

Safing Circuitry

Because of the explosives in the transducer and high voltages at the test points, safety features are imperative. A unit is placed in a barricade approved for such explosives prior to testing. Figure 3.11 shows this safety barricade. The port hole on top not only allows for exhaust should the device explode, but also provides a means to get the test cables to the unit being tested. There is an interlock in the front door of this chamber that is closed only when the door is secure.

This interlock is a contact switch that interfaces to ANTS via a two lead cable. Twenty-four volts used to energize a relay in the safing circuitry is fed out of the tester by one of the leads, through the interlock, and back into the tester by the other lead. If the interlock is not closed, the relay can not be activated. This relay labeled as K101 is shown in Figure 3.12. The path to ground for the relay coil is provided when a safe/arm key switch is in the safe position. The relay is wired so that it is self energizing. Once it is activated, the ground for the coil is provided through one of its own closed contacts. As long as the 24 volts is being furnished the relay will stay on. This is done since switching the key to the arm position removes the initial path to ground. This relay also supplies power to a lamp through one of its normally opened contacts to indicate that the safety chamber door is not secure. Another set of contacts is used to send a high signal to a GPIO input line when the relay is unenergized

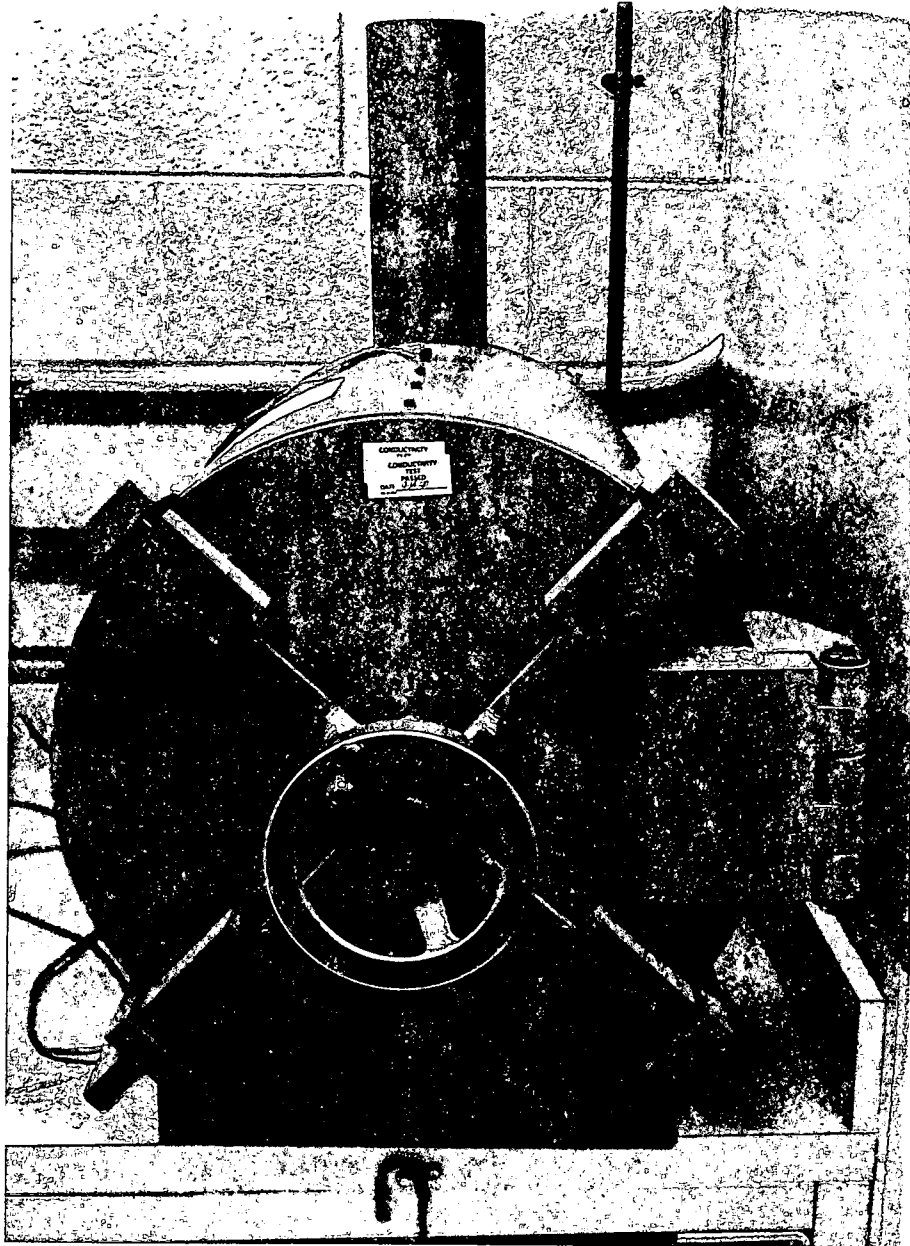


FIGURE 3.11: SAFETY BARRICADE

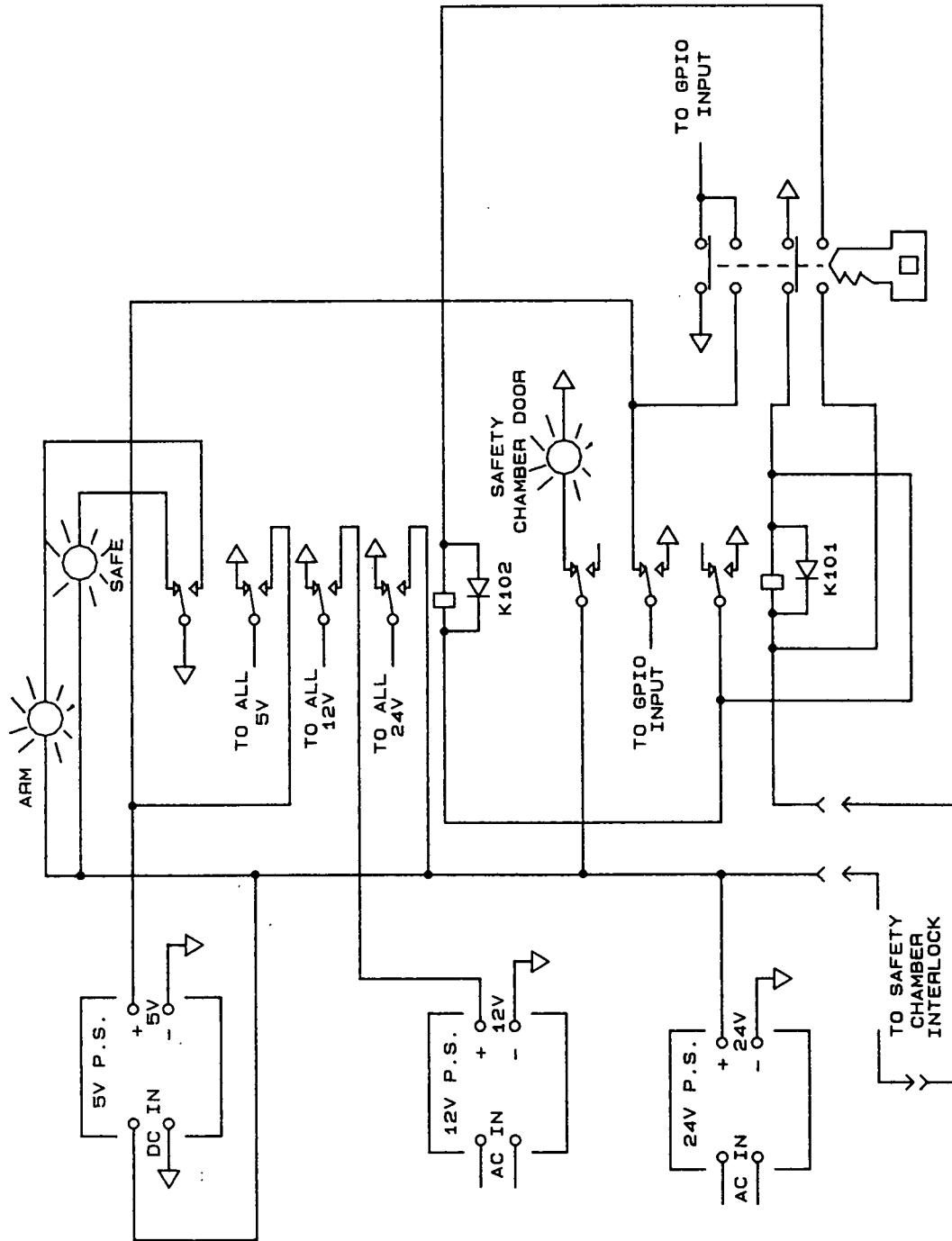


FIGURE 3.12: SAFETY CIRCUITRY

to communicate to the computer the position of the barricade door. When the relay is on, this contact is switched to ground, thus informing the controller that the barricade is secure. The relay will only become energized if the barricade door is closed and the key is in the safe position.

The purpose of this key switch is to provide a manual way to supply and remove power from the control chassis. This is done in compliance with safety procedures required at Mound. Opening the barricade door would not be a desirable way to shut down power if something critical happened to the transducer being tested. The closed contact that provides the ground for the self energizing relay is also the ground needed by another relay (K102) in the safing circuitry. To complete the circuit to energize this relay, the 24 volts is supplied through the key switch in the arm position. It is through this relay that all the hardware is powered. The five volt, 12 volt and 24 volt power supplies are fed through three closed contacts of this relay. The relays and integrated circuits get their voltages from these contacts. A fourth contact on the relay toggles a two position lamp between a green safe and a red armed indicator. This task is done by a relay instead of directly supplying all the power through contacts on the key switch because the current rating on the key switch contacts is not adequate. The coil of the one relay is the only element the key switch has to drive through one of its contacts. Another key switch contact is

used to send either five volts or ground to a GPIO input line so the computer knows the position of the key.

To summarize the function of the safing circuitry, the desired performance will be explained. The key must be in the safe position and the barricade door closed to energize the first relay. After the key is repositioned to arm the tester, the relay stays on because it attains the needed ground through one of its own contacts. If the chamber door is opened, the relay loses its power which removes the ground path for the coil. Closing the barricade door again will supply the voltage but since the key is in the arm mode no ground will be available to the coil. Therefore, the key must be returned to the safe position before the Automated Non-destructive Test System can be armed again.

Through a combination of the key switch being in the armed position and the first relay being activated, a second relay is energized. It is through this second relay that all power needed to perform the automated tests is furnished.

Fixtures

To perform all the required tests on the transducer, a method of connecting to the various tests points had to be devised. Access to these points is by specialized connectors. Since these types of connectors are precarious, extreme care in fixturing is required. Two fixtures, one for the Continuity tests and one for the

Insulation Resistance tests, were designed to be used with the test system. Both fixtures are side by side on the same base as shown in Figure 3.13.

The Continuity fixture is on the left side of the base. The transducer is placed on two poles and mating connectors are attached to the device. Each mating connector has two wires leading to it in order to maintain the four-wire resistance measuring technique. From the mating connectors, the cable carrying all these lines goes back into the test system and is integrated with the corresponding test selection relays for the Continuity tests.

The Insulation Resistance fixture, on the right in Figure 3.13, has a similar configuration except that it only needs one wire leading to each mating connector and uses higher voltage conductors. For ease in operation, some of these mating connectors are in a lid type form (not shown). This lid is placed on top of the transducer and a spring loaded arm clamps down on the lid and thus makes several of the required connections with one act. A cable from this fixture is correlated in the tester with the appropriate relays to select all of the Insulation Resistance tests.

When each transducer is tested, it is placed on one of the fixtures and then all of the appropriate connectors are attached to it. All of the tests corresponding to that fixture are performed. The unit is then moved to the other

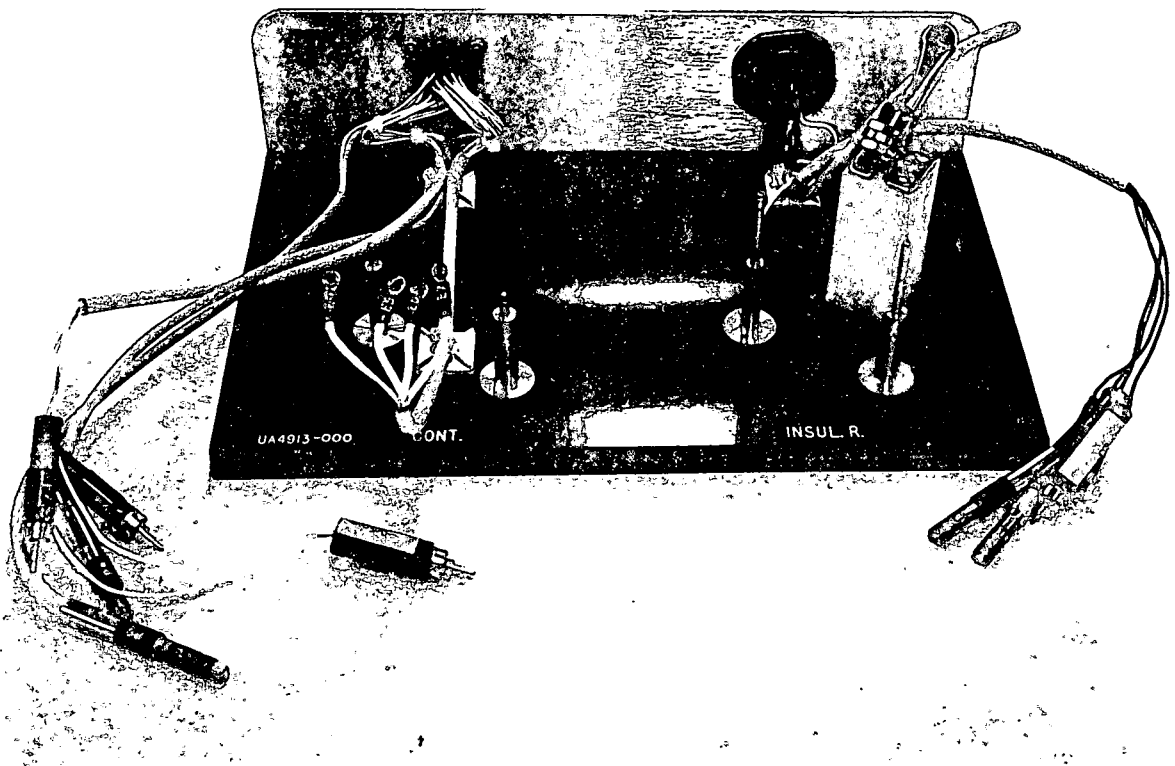


FIGURE 3.13: FIXTURES

fixture, all connections are made and all of the tests corresponding to that fixture are completed. The order of testing is determined by the operator via the software.

Simulators

A simulator is a device that is designed with some of the same characteristics as the transducer. The electrical characteristics of interest will be the same as those tested by the Automated Non-destructive Test System. The simulators contain no explosives and resemble the actual device enough to use the same fixtures. By using them at the beginning and the end of each day of testing, confidence in the test system is established. This procedure verifies that all the test results obtained that day are accurate and valid. Since the two types of tests performed by the Automated Non-destructive Test System verify different electrical conditions, two simulators are used.

The simulator for the Continuity tests is a hollow block of clear lexan with holes and connectors intricately placed to accommodate the connections for the tests. Inside of this box are precision resistors with values within the limits of the actual transducer. It is connected to the Continuity fixture the same way the device is and has the same measurements made. If the simulator fails, it is assumed that there is a fault in the test system. This problem must be corrected before transducers can be tested.

The Insulation Resistance simulator is more complex because it must be able to verify an accept and a reject condition for each test. Since an Insulation Resistance test is a method to verify the existence of a very high resistance, an open circuit would incorrectly be considered acceptable. If somewhere in the test circuit a connection is not made or a wire is broken, the result would be the same as an accepted unit. The simulator proves that none of these faults exist by defining a test to be performed on a resistance known to be below the acceptable value.

On the other hand, the simulator must also be capable of verifying that nothing is shorted together in the tester or fixture. A resistance greater than the minimum requirement is used to eliminate the possibility of false rejects.

Similar to the Continuity simulator, the Insulation Resistance simulator consists of a lexan box with the appropriate connectors to mate with the fixture. On the inside of this box, wires attached to the connectors run out of the lexan and into a box with two rotary switches. One switch isolates two pins on the connector to single out a particular test. The other switches between two resistors in the box, one just above the limit of ten megohms to simulate an accept condition and the other just below the limit to mimic a rejected unit. In the latter case the current flowing through the circuit will be too high and will cause the comparator circuit to trip. Because an acceptable Insulation Resistance test is

verifying an open circuit, reject conditions need to be simulated to confirm that the tester is functioning properly. When this simulator is tested, the software performs each test twice, once looking for an accept condition and once looking for a reject status. The software instructs the operator where to position the switches and then performs the corresponding tests. If these conditions are not met, the software instructs the operator to double check the switch positions. If the switch positions are verified to be correct it is assumed that there is something wrong with the tester. The type of error is documented to aid in finding and correcting the problem.

Both simulators are verified during the calibration of the test system. Tests on the simulators are then made prior to testing any transducer. This establishes the validity and accuracy of the test results obtained by the Automated Non-destructive Test System.

CHAPTER IV

SOFTWARE

The Automated Non-destructive Test System is controlled by a BASIC operating system. The test program consists of many routines written to perform specific tasks needed to test the transducer, store the data, and make the program user friendly.

Upon power up of the test system, the BASIC system is loaded into memory from a floppy disk which is in drive 0 of the HP9122 disk drive. This includes all the binaries and drivers needed for interfacing to the other equipment and the operator via the monitor and keyboard. After this is accomplished, the system loads and runs an auto executable program called "AUTOST". This program is simply used to call the main testing program into memory and then to run it. The flow chart for the main testing program is found in Appendix A.

Program Setup

The first thing the main program does is graphically display an introduction screen which consists of the title of the test system and further instructions to execute the program. Upon execution, the program branches to the routine which defines the memory location for the

constants. In BASIC they are given names which have significance related to their function. The resistance limits for the three Continuity tests are set up in two one by three dimensional arrays and are named "R_up" and "R_low". The tolerances for the high voltages are added and subtracted from the nominal value to define the upper and lower limits for the voltage requirements for the Insulation Resistance tests. These limits are stored in BASIC arrays named "Up_volt_lim" and "Low_volt_lim". Status bits are given names which will be used in condition testing routines.

The main program branches to a routine which initializes all the variables which are used to store the test results. This routine is executed before every test to clear the memory locations of previous test data. By doing this, the validity of the test results is assured.

Defining the addresses of all the equipment is the next task to be accomplished by the software. Each piece of equipment is configured to perform its specific function.

There are four monitoring routines which check the status of the GPIO interface bits. The first one examines the condition of the line that is tied to the safe/arm key switch in the hardware. A high state, a binary one, indicates to the software that the key is in the safe position and the program will continue. If a low or a binary zero is detected on this bit, a message to return the key to the safe position is flashed on the screen. In

this case the program will not continue until this is done. After this is accomplished, the desired high state will be detected and the routine will be exited. When performing a test, a routine that does just the opposite is executed. The key switch must be in the armed position to supply power to the test circuits.

Two more routines which operate in the same way are used to detect the state of the safety chamber door and the reset switch of the comparator circuits. The door routine is executed every time the door must be closed. A routine to ensure that the comparator circuits are in the reset state is used to verify that the system is ready to perform the Insulation Resistance tests.

These four program segments are called at various times throughout the execution of the test program to perform their designated tasks.

A display of the main menu is the next operator interfacing function performed by the software. It provides the option to test a unit, run the simulators or access the stored data for editing and printing purposes.

Testing

To verify that the tester is functioning properly, the first choice must be to run the simulators. The primary difference between the testing of the simulators and of an actual transducer is the storing of the test data. Any variation in the testing procedure will be detailed in the

explanation of each type of test.

Entering Data

After the selection to test a unit or run the simulators has been made, various information pertaining to the lot of transducers is entered by the operator. This information is used to identify when the lot was built, when it was tested, who tested it, at what stage of its development it was tested, and the reason for performing these tests on it. The different development stages of a transducer consists of being exposed to a variety of environmental conditions such as extreme temperatures and vibrational shock. A unit is tested on the Automated Non-destructive Test System after various environmental tests to verify that it was not damaged by them. Reasons for testing the transducer are for obtaining development or process data, accepting a product or testing stockpile samples. All these questions are answered by completing prompts as they appear on the screen of the monitor.

The above information is entered one time for the entire lot. However, a serial number for each unit is entered for every transducer. When testing the simulators, the serial number is labeled as such by the software when that selection is made from the main menu.

After entering this information, the operator is then instructed to choose between performing Continuity tests, performing Insulation Resistance tests, storing the test results or ending the testing session.

Continuity Tests

The routine to perform the Continuity tests is entered by making the appropriate selection from the above mentioned menu. The instruction to install the transducer in the Continuity fixture is given. If testing the simulator, the instructions refer to the simulator and all of the testing techniques are the same as for an actual device. The question is then asked whether all three or just one or two of the Continuity tests are to be made. If all are to be tested the routine makes the measurements in an automated fashion. One or more tests can be singled out for individual testing if deemed necessary for investigative purposes. This allows for the test in question to be re-tested without having to run through all of the tests. All of the tests must be made before the test will be considered complete and the data stored.

If this question is answered with the "Y" prompt then all of the resistance measurements are made. After executing the routine to instruct the operator to "ARM" the tester by switching the safe/arm key to the arm position, the program increments through all three of the tests. Each test is performed when a subroutine corresponding to that Continuity test number is called. These subroutines close the necessary relays to connect the Keithley Micro-Ohmmeter to the points under test. The relays are closed when the appropriate GPIO interface output bits are set by a software instruction. The meter is then instructed to take a four-wire resistance reading. After

waiting one second, this value is entered into the corresponding variable in the computer memory. The GPIO interface lines are cleared, thus de-energizing the relays. An instruction to "SAFE" the tester by returning the safe/arm key to the safe position is given. The routine to verify that this has been accomplished is executed. The newly obtained resistance value is then rounded to meet the precision required by the specifications of the transducer.

If the option to not test all of them is made, the operator is then instructed to enter in the test numbers to be tested. After the tester is "ARMED", the testing routine only branches to the subroutines necessary to make the selected tests.

After testing is complete the results are printed out on the monitor screen for the operator to review. If any of the results indicate that one of the connectors to the unit was not secure during the test, the tests in question can be re-tested after checking the connections. Connecting to the transducer for the tests performed by the Automated Non-destructive Test System is a very tedious task, even for a trained operator. That is why the capability to test more than once is provided.

If all of the continuity tests look valid, the software branches back to the menu that gives the type of test choices.

Insulation Resistance Tests

The Insulation Resistance testing routine is selected from this menu. The first thing this routine does is to instruct the operator to connect the transducer or the simulator to the Insulation Resistance fixture. When testing a transducer, the process is similar to that of the Continuity testing routine. The operator is prompted to select the number of tests to be performed and to "ARM" the tester. If the choice to automatically perform all nine I.R. tests is made, the routine will increment a counter corresponding to each Insulation Resistance test. Every time the counter is incremented, a subroutine will be called to execute that corresponding test. These subroutines close the appropriate relays needed to make the tests. After a set of relays is closed, the software branches to the routine that checks the state of the comparator circuit by polling the appropriate GPIO Interface input bit. This is accomplished by software instruction statements. A high state on this bit indicates that the comparator circuit was not triggered. Under this condition the program continues and the test result is considered acceptable. However, if this bit is low, the comparator circuit has been triggered thus interrupting the test circuit. After detecting this condition, the software displays instructions to "SAFE" the tester, as described earlier, and then to reset the I.R. circuit. As described in the Hardware chapter, resetting this circuit involves

depressing a push button on the front of the control chassis. The program will continuously loop through the reset I.R. routine until the circuit is reset. After the circuit is reset, the test is labeled as a reject and the next Insulation Resistance test is started.

If the operator chooses to perform only a few of the tests, the prompt to enter in the desired test numbers must be answered. Only the tests corresponding to the ones selected will be executed.

After the Insulation Resistance tests have been completed the results are displayed on the screen of the monitor. This gives the operator the opportunity to verify that the unit was connected properly and that the results are valid. There are no values associated with these tests, just an accept or reject status based on whether the comparator circuit tripped. The data is not stored until all nine of these tests are completed and verified.

If the simulator is being tested, the serial number is labeled as such and a routine for verifying the insulation resistance simulator is called. This routine confirms that an accept and reject condition for each of the Insulation Resistance tests is satisfied. This is done in conjunction with the switching box of this simulator. The software instructs the operator to position the two switches on the box for a specified condition on a particular test. One switch selects the test and the other switches between the accept and reject condition.

The software keeps track of which test is being performed. For each test on the simulator, the actual testing routine is branched to twice from the simulator routine. The first time an acceptable condition is required to proceed. The second time a reject must be detected and the comparator circuit must be reset for the software to continue to the next test. Each test of the Insulation Resistance simulator must meet the accept and reject requirement to be considered a "passed" test. If both of these conditions are not satisfied the test is labeled as a "failed" test. The operator is given the opportunity to verify that the switches are in the proper positions and to run the tests again. A failed simulator test indicates that the test system requires maintenance.

Storing Data

After all of each type of test is completed and the operator reviews the results, the program returns to the menu to choose the type of test to be performed, to store the data or to end the testing session. The option to store the data must be made. When this is done, a routine is called that displays all of the test results of both the Continuity tests and the Insulation Resistance tests. It also verifies that all of the tests have been completed. If not all of the tests have been made, the program will notify the operator of this and will not store the data. Upon acknowledgment from the operator, the software will return to the menu to choose the type of test to be

performed.

If all of the tests are completed for the given transducer the test results are printed out on the printer. Figure 4.1 is such a print out. The print out generated when the simulator is tested varies slightly because some of the header information does not apply. The print out from the simulator is shown in Figure 4.2.

The data from a transducer is formatted to be stored on a data disk. The test results are associated with identifying codes and then placed in a string variable to be stored in a random access ASCII formatted file. The characteristics of this data string are defined by Sandia National Laboratory in Albuquerque (SNLA) for all weapon components. This is done for transmitting and storing purposes. The standard ASCII format can be read by other operating systems. Any test results obtained from the simulators does not get stored on a disk.

Editing Data

From the original menu the option is given to edit the data. This selection allows the information that was entered by the operator to be changed. None of the actual test results can be accessed by the program. Due to human error, mistakes such as transposing serial numbers or entering in the wrong date can occur.

Using the print out as a guide, the record number that the mistake appears in is selected. The data string stored in the file associated with this record number is brought

AUTOMATED NON-DESTRUCTIVE TEST SYSTEM CONTINUITY/INSULATION RESISTANCE TESTER

PRODUCT SPECIFICATION: 123456-A
PART NUMBER: 123456-01
LOT NUMBER: 0001

SOFTWARE: SW123456-A
DATE: 11-12-90
TEST CODE: 00
DATA SOURCE CODE: X

SERIAL NUMBER: 000012

DATE MANUFACTURE CODE: 290

TEST	Limits(Ohms)		VALUE(ohms)	STATUS
CONT TEST NUMBER 1	x.xxxx	y.yyyy	z.zzzz	ACCEPT
CONT TEST NUMBER 2	x.xxxx	y.yyyy	z.zzzz	ACCEPT
CONT TEST NUMBER 3	x.xxxx	y.yyyy	z.zzzz	ACCEPT
I.R. TEST NUMBER 1				ACCEPT
I.R. TEST NUMBER 2				ACCEPT
I.R. TEST NUMBER 3				ACCEPT
I.R. TEST NUMBER 4				ACCEPT
I.R. TEST NUMBER 5				ACCEPT
I.R. TEST NUMBER 6				ACCEPT
I.R. TEST NUMBER 7				ACCEPT
I.R. TEST NUMBER 8				ACCEPT
I.R. TEST NUMBER 9				ACCEPT

FIGURE 4.1: TRANSDUCER PRINTOUT

**AUTOMATED NON-DESTRUCTIVE TEST SYSTEM
CONTINUITY/INSULATION RESISTANCE TESTER**

PRODUCT SPECIFICATION:

PART NUMBER:

LOT NUMBER:

SOFTWARE: SW123456-A

DATE: 11-12-90

TEST CODE:

DATA SOURCE CODE:

SERIAL NUMBER: SIMULATOR

DATE MANUFACTURE CODE:

TEST	Limits(Ohms)	VALUE(ohms)	STATUS
CONT TEST NUMBER 1	x.xxxx y.yyyy	t.tttt	ACCEPT
CONT TEST NUMBER 2	x.xxxx y.yyyy	t.tttt	ACCEPT
CONT TEST NUMBER 3	x.xxxx y.yyyy	t.tttt	ACCEPT
I.R. TEST NUMBER 1			ACCEPT
I.R. TEST NUMBER 2			ACCEPT
I.R. TEST NUMBER 3			ACCEPT
I.R. TEST NUMBER 4			ACCEPT
I.R. TEST NUMBER 5			ACCEPT
I.R. TEST NUMBER 6			ACCEPT
I.R. TEST NUMBER 7			ACCEPT
I.R. TEST NUMBER 8			ACCEPT
I.R. TEST NUMBER 9			ACCEPT

FIGURE 4.2: SIMULATOR PRINTOUT

into the computer's memory. The string is searched for the identification codes of the operator entered data that can be changed. Variables allocated in memory are filled with this information. The operator selects from a menu which parameter needs to be edited. The data in the temporary variable is displayed on the screen and is changed by being typed over. After the change is verified by the operator, the variable strings are concatenated back into the single data string to be stored on the disk. This string overwrites the original string stored in that file.

After this is accomplished, the program returns to the introduction screen.

CHAPTER V

CALIBRATION

Calibration of the Automated Non-destructive Test System is required to be assured of the validity of the test data. The tester is calibrated periodically by the EG&G Mound metrology laboratory using a procedure and software written for this purpose. The calibration is traceable to the National Institute of Standards and Technology (NIST), formerly the National Bureau of Standards (NBS).

Simulator Verification

As part of the calibration, the electrical characteristics of the simulators are verified. The three precision resistors in the Continuity simulator are measured with a calibrated ohmmeter from the electrical standards laboratory. This measurement employs the four wire resistance measuring technique described earlier. Each set of leads from the standard ohmmeter is attached to pins from mating connectors. These pins are inserted into two desired points in the simulator connector. The reading obtained from the two desired points is compared to the original design value. This is done for all three of the resistance values that constitutes the Continuity

simulator. These values are recorded as part of the history of the test system.

The standard ohmmeter is connected to the Insulation Resistance simulator the same way as the Continuity simulator. For each of the two points in the connector the meter is used to take two measurements. A 12 megohm resistor and a ten megohm resistor in the simulator switching box are checked. The two different resistor values are used to simulate an accept and a reject condition for each of the nine Insulation Resistance tests. These values are verified and recorded.

Equipment Calibration

Each of the digital meters is calibrated using references from the electrical standards laboratory. Two ranges on the Keithley Micro-Ohm Meter are calibrated with standard resistors. Each of the standard resistors is plugged directly into the meter. The meter must read within 0.01 percent of the standard resistors. If one does not, the discrepancy must be noted and adjustments made to the micro-ohm meter.

The Hewlett Packard meter is calibrated for voltage measurements since that is its only parameter used by the Automated Non-destructive Test System. A standard voltage power supply is used to provide an A/1000 volt signal and a B/1000 volt signal to the meter. These represent the voltages seen by the meter across the voltage divider network. The meter must read these values within the

acceptable tolerances. The same procedure for noting discrepancies and making adjustment is followed as for the Keithley Micro-Ohm Meter.

At the bottom of the front panel is the calibration door shown in Figure 3.6. Test points for calibrating the five volt, 12 volt and 24 volt power supplies are accessed by opening the door. After connecting a standard voltmeter across TP105 and ground the 24 volt adjust terminal is regulated until the standard meter reads within ten percent of the nominal 24 volts. The 12 volt and five volt power supplies are calibrated the same way by connecting the standard voltmeter across TP106 and ground, and TP107 and ground and making the needed adjustments to the appropriate terminals.

Software Aided Calibration

The remainder of the calibration is dependent on software control. A program separate from the operating program is written for this task. This program is used by technicians from the electrical metrology laboratory only.

Similar to the operating program, the calibration software is written in the BASIC language. Memory allocation is configured the same way for variables and test parameters. The program consists of many routines to perform various tasks. Most of the routines interface to the technician by giving instructions and relaying what the routine is doing. The flow chart of this program is found in Appendix B.

Comparator Circuits

After the program is loaded into memory and an introduction screen is displayed the calibration process begins. The first task to be accomplished must be to verify that the A volt and the B volt power supplies are performing at the expected levels. The standard voltmeter is connected across TP101 and TP102 in the calibration panel. This connection places the standard meter directly across the output of the high voltage power supplies. A software routine is then called to close the needed relays to turn on the B voltage power supply. The voltage value is verified on the standard meter. A second software routine is used to verify the A voltage power supply. The voltage being supplied by both sources is noted as "as found" values. The reading on the Hewlett Packard digital meter in the Automated Non-destructive Test System must be equal to the readings on the standard meter divided by 1000. This verifies the voltage divider network in the test circuit. This data is used for historical purposes since calibrating the comparator circuits involves taking the high voltage power supplies out of limits.

The comparator circuits are calibrated by setting the leakage current values that will cause the comparator circuit to be triggered. The calibrated Insulation Resistance simulator provides the needed resistance at the device under test terminals to cause an unacceptable leakage current. This is achieved by placing the accept/reject switch on the simulator switching box in the

reject position. The test selection switch is positioned according to which comparator circuit is being calibrated. The first test must be selected when calibrating the circuit that corresponds to the A volt test. Since the remaining tests all use the same circuit in conjunction with the B volt test, the selection is arbitrarily made for the second test. The variables A and B were defined previously as two different high voltage levels. The software gives the instructions and keeps track of which test is being selected. The leakage current is measured by removing a shorting plug, TP104, in the calibration panel, Figure 3.6, and placing a standard ammeter in series in the return leg of the comparator circuit. The software activates the circuit as would be done during an actual test except there is no time limit. After the technician "arms" the tester by placing the safe/arm key in the arm position, the circuit functions until the key is returned to the safe position. While the circuit is functioning, the potentiometer which determines the reference voltage for the input of the comparator is adjusted until the leakage current no longer causes a reject. The terminal for this potentiometer is located behind the calibration door. The reset button on the front panel is used to continuously reset the tripped comparator until the potentiometer adjustment no longer causes a reject.

The high voltage power supply is adjusted until the standard ammeter reads a value just below the acceptable maximum leakage current. For the A volt tests this value

is aa.a microamps and for the B volt test the value is bb.b microamps. As defined earlier, aa.a and bb.b represent the values of the two maximum leakage currents. After the leakage current is established, the potentiometer of the comparator circuit is adjusted until it is just sensitive enough to cause a reject at the defined current. The standard ammeter is removed from the circuit and the shorting plug is placed back in the circuit.

The above procedure is followed for calibrating both of the comparator circuits one at a time.

The two high voltage power supplies must now be calibrated since they were adjusted out of limits earlier. The switching box of the Insulation Resistance simulator is switched to the accept position. A standard voltmeter is connected across TP101 and TP102 in the calibration panel, Figure 3.6, as was done when verifying the "as found" voltage values. The power supplies are calibrated by making the needed adjustments to the appropriate terminals on the calibration panel until the standard voltmeter reads the desired voltage. The voltage must be $A \pm C$ volts for the A volt power supply and $B \pm D$ volts for the B volt power supply, where C and D are the respective tolerances. The voltage read by the Hewlett Packard Digital Multimeter in the test system must be equal to that read by the standard meter divided by 1000 ± 0.5 percent. The one half percent is the maximum allowable error of the voltage divider network. These values are recorded as the "as left" values.

The values that are recorded as the leakage currents are calculated by dividing the full scale voltages by the acceptable resistances measured on the Insulation Resistance simulator. This is done for both the "as found" case and the "as left" case. This provides traceable records for how the test system was functioning before and after calibration.

Timing Verification

Since the specification of the transducer requires that the device be exposed to the high voltages for a given time, the timing of the system clock must be calibrated. This is achieved by connecting a standard storage scope across TP102 and TP103 in the calibration panel, Figure 3.6. This places the scope across the voltage divider network. A selected test on the Insulation Resistance simulator is placed in the accept state. The software runs through the testing procedure after the safe/arm key is placed in the arm position. A trace on the scope is generated. This reading is recorded from the 50 percent points on the trace and must fall between two and nine seconds.

System Check

Both the Continuity simulator and the Insulation Resistance simulator are connected to their appropriate fixture. The entire testing process is executed for all tests.

The results of the Continuity tests are compared to those values obtained from measuring the Continuity simulator with the standard meter. All values must fall within the acceptable range.

By performing all of these tests, it is verified that everything is configured and functioning properly.

CHAPTER VI

SUMMARY AND CONCLUSIONS

Before fabrication of the Automated Non-destructive Test System was started drawings were generated and a general software development plan was devised. As fabrication proceeded it became apparent that there were better ways to achieve the desired effect. This included some minor alterations to the hardware design.

One such alteration consisted of the addition of the Keithley Digital Micro-ohmmeter. The original design used the Hewlett Packard Digital Multimeter to make the three Continuity measurements in addition to measuring the voltages. Even though the Hewlett Packard meter has the capability of making a four-wire resistance measurement, it proved not to be stable in the milli-ohm range. This left the only measurement made by the Hewlett Packard to be the voltage readings. The addition of the Keithley meter resulted in the changing of some of the switching circuitry. The Hewlett Packard meter had to no longer be switched between taking resistance readings and measuring the high voltages. By having two meters dedicated to specific tasks some relays were eliminated.

Software development evolved around the fabrication of the system. The control and timing of the tests were

established at this time. During this development it was determined that the comparator circuits were too sensitive. They had a tendency to trigger when the high voltage was first applied even though the reference voltage was never exceeded. After investigating this problem, it was realized that it was the sudden change in voltage that was causing this false trigger. The solution was to let the voltage ramp up to the desired value using the internal rise time of the Venus high voltage power supply. This was accomplished in the software by controlling the order in which the relays were closed.

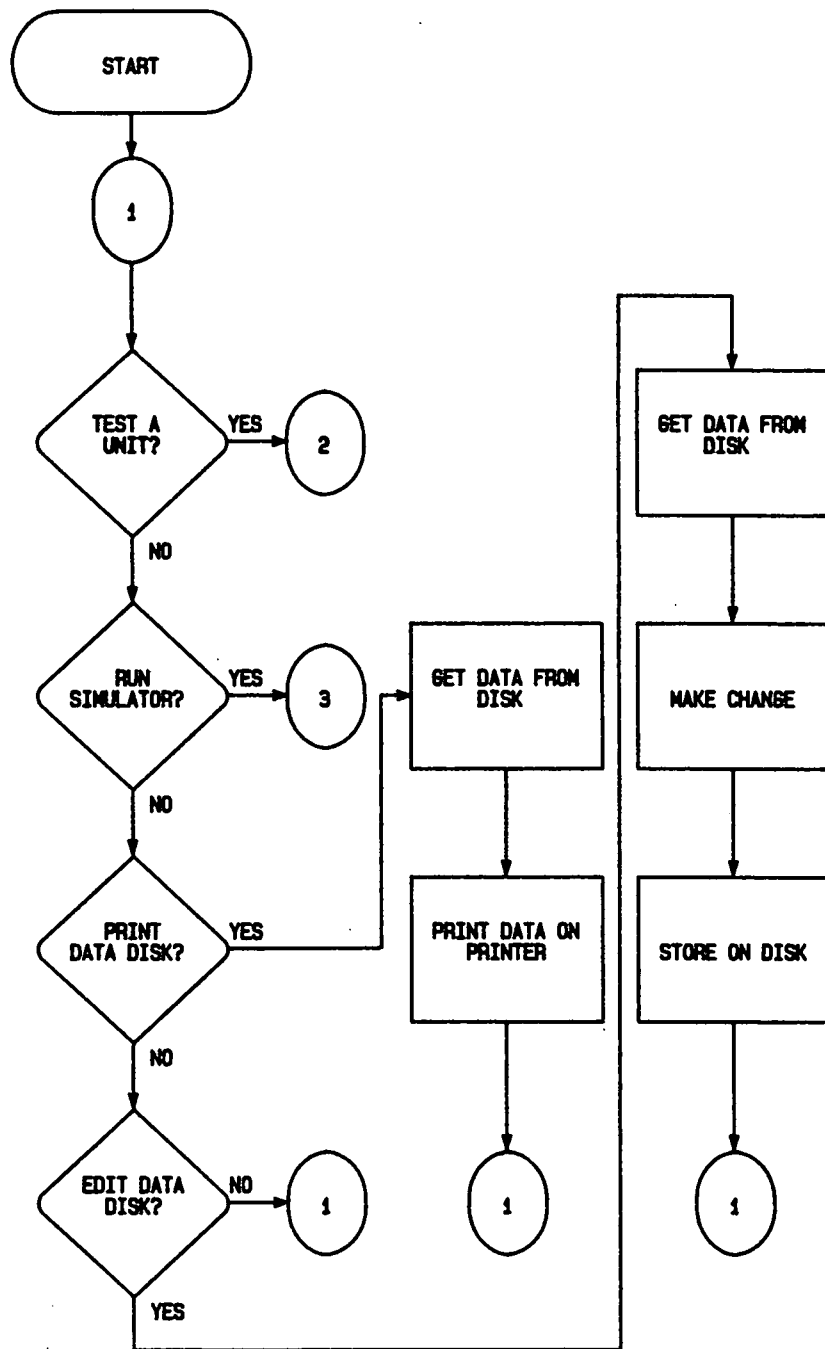
During the first stages of development of the system a simulator was used in testing the hardware. Everything functioned satisfactory. The first transducers to be tested on the system were mock inert units. When testing these a failure status on one specific Insulation Resistance test kept recurring. This raised the concern over whether all the transducers built had the same fault or whether ANTS was malfunctioning. The integrity of the tester was verified by use of the simulator. After scrutinizing the units, it was determined that they met all the qualifications. It became apparent that there was some form of interface problem between the fixture and the actual transducer that did not occur between the fixture and the simulator. After further investigation it was discovered that a thin clear coating of epoxy type material existed on the case of the device. This coating acted as a dielectric between the two points of high voltage

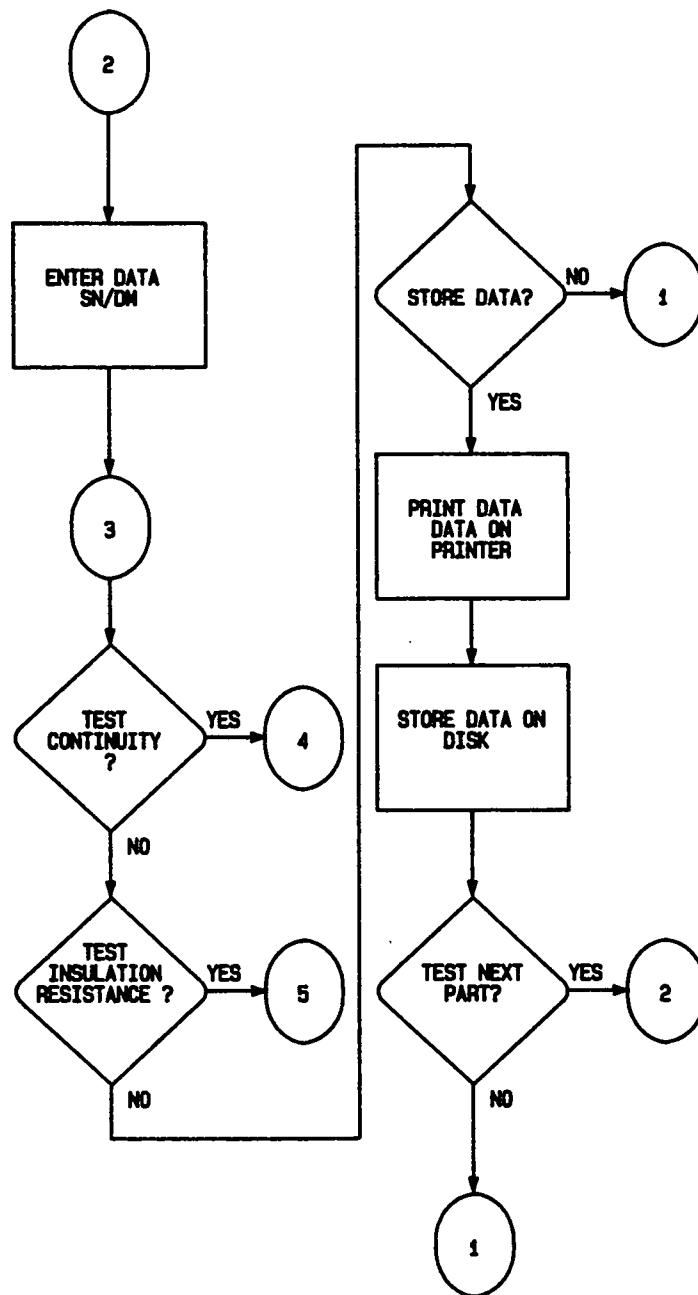
application. A charge was building up on these two "plates", thus resulting in a capacitor type behavior. This problem was eliminated by modifying the fixture so the contact to the case would be in a location where none of this coating would be present.

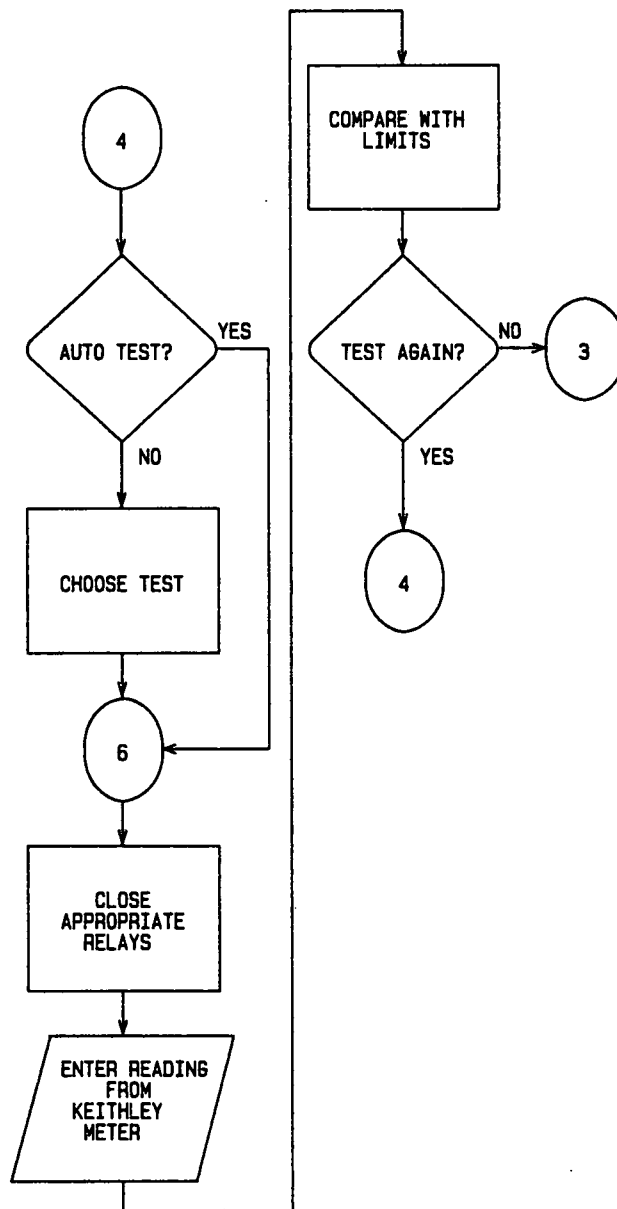
A general calibration plan was outlined during the design of ANTS. This included test points to all the voltages and adjust terminals to the various potentiometers to be located behind the calibration panel on the front of the control chassis. The specifics were developed after the fabrication was complete.

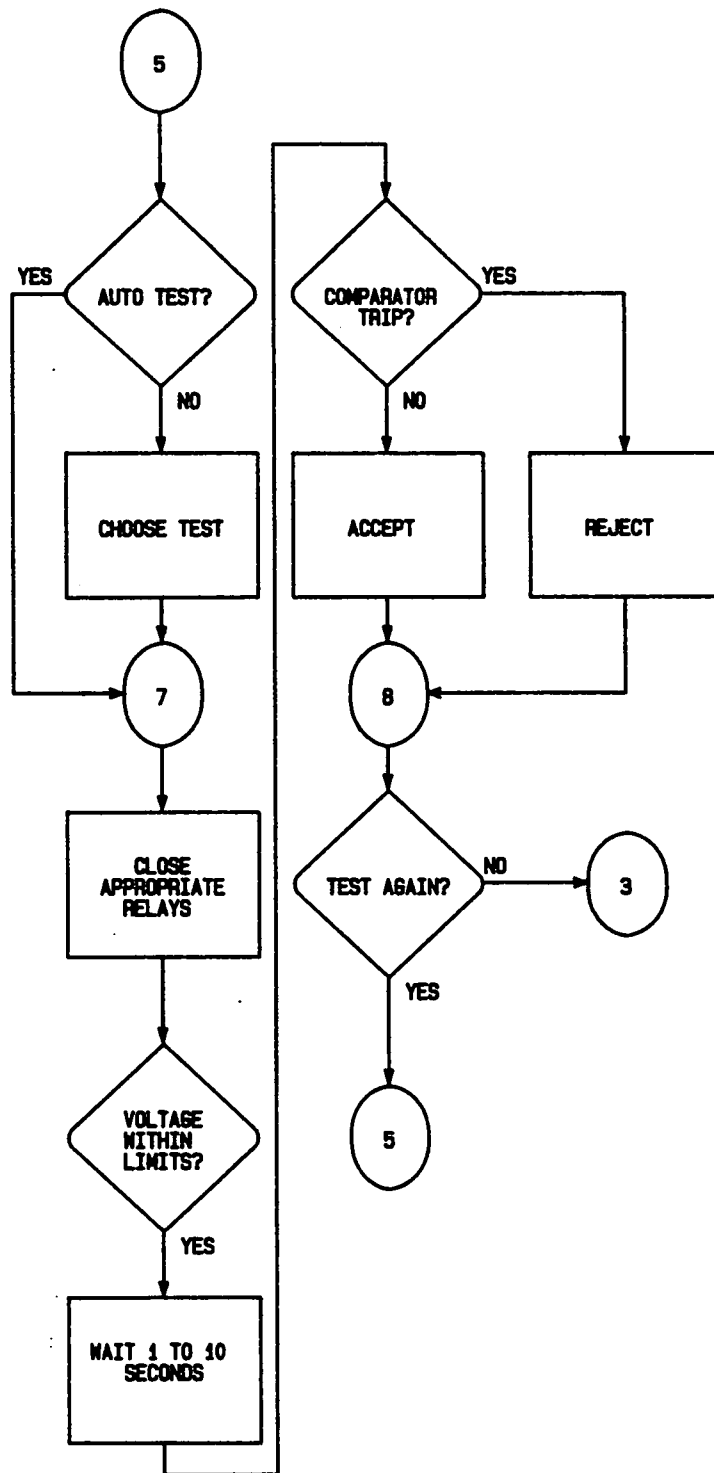
The Automated Non-destructive Test System was completed in time to support development testing of the transducers at the Mound. This provided an automated means of testing the units and storing the data for later comparisons with production units. The test system has proved to be very reliable in detecting errors in Continuity and poor Insulation Resistances.

APPENDIX A
OPERATION FLOWCHART

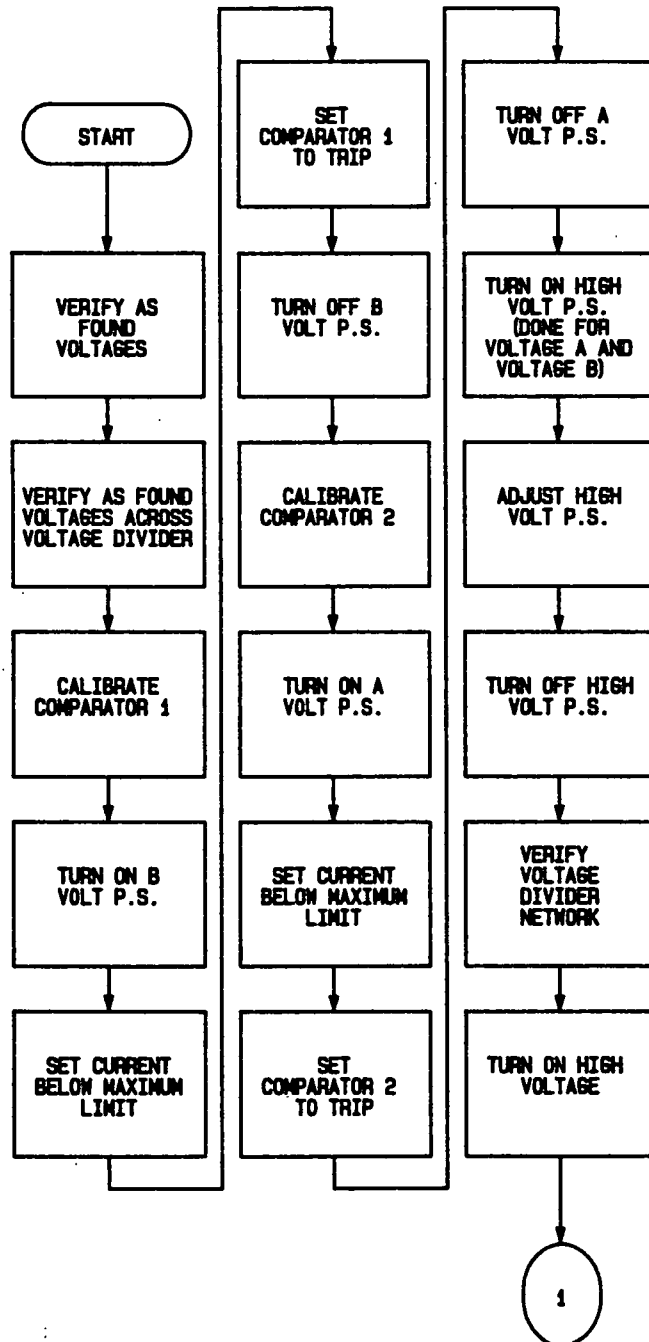


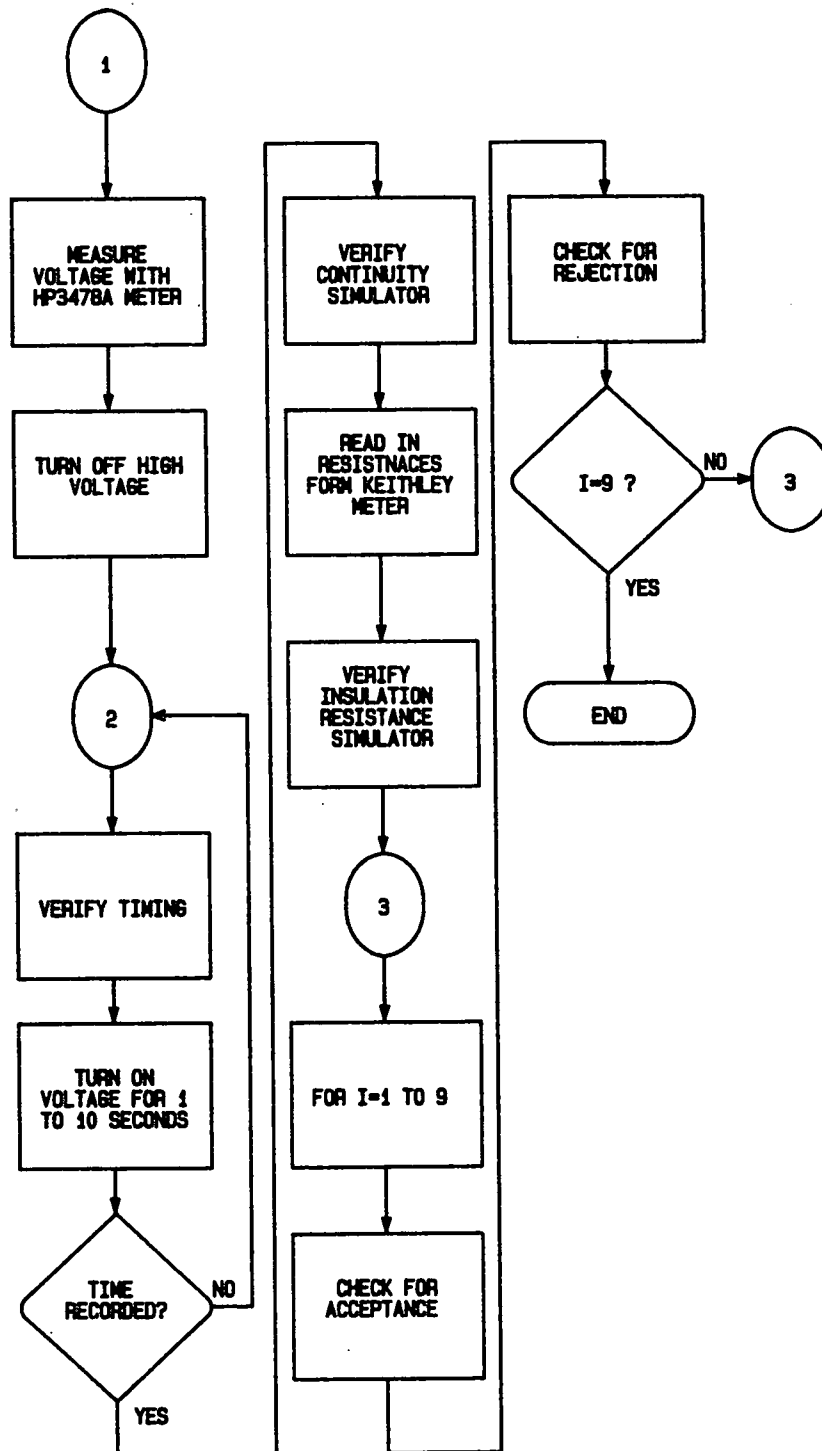






APPENDIX B
CALIBRATION FLOWCHART





APPENDIX C
SELECTED OPERATION SOFTWARE LISTING

```

240!*****
250!*****
260 Intro_screen: ! DISPLAYS INTRO SCREEN
270  DISP
280  PRINT CHR$(12)
290  GRAPHICS ON
300  GCLEAR
310  MOVE 22,70
320  CSIZE 30,.5
330  LABEL "ANTS"
340  CSIZE 8,.4
350  MOVE 2,65
360  LABEL "CONTINUITY-INSULATION RESISTANCE TESTER"
370  MOVE 44,55
380  LABEL Am$
390  DISP "Press ANY key when ready"
400  ON KBD GOTO Start
410 Loop_a:GOTO Loop_a
420 !*****
430 !*****
440 Start:!
450  IF Re<>0 THEN OUTPUT KBD USING "#,K","|"
460  GOSUB Init_const
470  GOSUB Init_test_var
480  GOSUB Addressing
490  GCLEAR
500  DISP ""
510  GOSUB Safe_tester
520  PRINT CHR$(12)
530  GOSUB Reset_ir
540  GOSUB Main_menu
550  GOSUB Ds_menu
560  GOSUB Data_disk
570  GOSUB Header_info
580  GOSUB Header_verify
590 !*****
600 !*****
610 Main_menu: ! GIVES TEST AND DATA CHOICES
620  GCLEAR
630  New_lot=0
640  Name$="***** MAIN MENU *****"
650  DATA " TEST NEW LOT "
660  DATA "TEST_NEW"
670  DATA " CONTINUE TESTING "
680  DATA "CONT_TEST"
690  DATA " RUN SIMULATORS "
700  DATA "SIM"
710  DATA " EDIT DATA DISK "
720  DATA "EDIT_DATA"
730  DATA " PRINT DATA DISK"
740  DATA "PRINT_DATA"
750  RESTORE 640

```

```

760  Menue_items=5
770  GOSUB Menue
780  OUTPUT KBD USING "#,K";" {"      ! USER SOFTKEYS
790  OUTPUT KBD USING "#,K";" |"      !SOFTKEYS ON
800  ON KEY 1 LABEL "UP" GOSUB Move_down
810  ON KEY 2 LABEL "DOWN" GOSUB Move_up
820  ON KEY 3 GOTO Loop_b
830  ON KEY 4 LABEL "SELECT" GOTO Selecta
840  ON KEY 5 GOTO Loop_b
850  ON KEY 6 GOTO Loop_b
860  ON KEY 7 GOTO Loop_b
870  ON KEY 8 GOTO Loop_b
880  ON KBD GOTO Loop_b
890  Loop_b:GOTO Loop_b
900  Selecta:OFF KEY
910  OUTPUT KBD USING "#,K";" |"
920  OFF KBD
930  PRINT CHR$(12)
940  IF Select$="EDIT_DATA" THEN GOTO Edit_data
950  IF Select$="PRINT_DATA" THEN GOTO Print_data
960  IF Select$="SIM" THEN GOTO Simulator_ck
970  IF Select$="TEST_NEW" THEN New_lot=1
980  RETURN
990  !*****
1000 !*****
1010 Ds_menu:!                SELECTS DATA SOURCE CODE
1020 IF NOT (New_lot) AND Re=0 THEN RETURN
1030 GCLEAR
1040 Name$="***** SOURCE CODE MENUE *****"
1050 DATA " PRODUCTION TESTING (NO DATA DISK)"
1060 DATA "PRO_TEST"
1070 DATA " ENGINEERING EVALUATION (CODE L)"
1080 DATA "L"
1090 DATA " PRODUCT ACCEPTANCE (CODE S)"
1100 DATA "S"
1110 DATA " PRODUCT REACCEPTANCE (CODE R)"
1120 DATA "R"
1130 DATA " STOCKPILE SAMPLE (CODE Q)"
1140 DATA "Q"
1150 DATA " QAIA TESTING (CODE Z)"
1160 DATA "Z"
1170 DATA " DEVELOPMENT TESTING AT MOUND (CODE D)"
1180 DATA "D"
1190 RESTORE 1040
1200 Menue_items=7
1210 GOSUB Menue
1220 OUTPUT KBD USING "#,K";" |"
1230 ON KEY 1 LABEL "UP" GOSUB Move_down
1240 ON KEY 2 LABEL "DOWN" GOSUB Move_up
1250 ON KEY 3 GOTO Loop_c
1260 ON KEY 4 LABEL "SELECT" GOTO Selectb
1270 ON KEY 5 GOTO Loop_c

```

```

1280 ON KEY 6 GOTO Loop_c
1290 ON KEY 7 GOTO Loop_c
1300 ON KEY 8 GOTO Loop_c
1310 ON KBD GOTO Loop_c
1320 IF Re<>0 THEN
1330     CONTROL CRT;1,18
1340     PRINT "DATA SOURCE CODE ON DISK IS "&Data_source&".  MAKE SELECTION"
1350 END IF
1360 Loop_c:GOTO Loop_c
1370 Selectb:OFF KEY
1380 OUTPUT KBD USING "#,K";"|"
1390 OFF KBD
1400 PRINT CHR$(12)
1410 IF Select$="PRO_TEST" THEN
1420     Select$="PRODUCTION TESTING"
1430     IF Re<>0 THEN Ds_menu
1440     Pro_test=1
1450 END IF
1460 Data_source$=Select$
1470 Output$="DATA SOURCE CODE "&Data_source$
1480 RETURN
1490 !*****
1500 !*****
1510 Menue: ! CONTROLS ALL MENUE CHOICES
1520 !
1530 Longest=0
1540 FOR I=1 TO Menue_items
1550     READ Menue$(I)
1560     READ Progr$(I)
1570     IF LEN(Menue$(I))>Longest THEN Longest=LEN(Menue$(I))
1580 NEXT I
1590 !
1600 PRINT CHR$(12)
1610 Min_row=INT(10-(Menue_items/2))+2
1620 Row=Min_row
1630 Max_row=Min_row+Menue_items-1
1640 IF LEN(Name$)>Longest THEN Longest=LEN(Name$)
1650 Col=INT(40-(Longest/2))
1660 CONTROL CRT;Col-1,Row-2
1670 PRINT Name$;
1680 FOR Row=Min_row TO Max_row
1690     CONTROL CRT;Col,Row
1700     IF Row=Min_row THEN
1710         PRINT CHR$(129);CHR$(140);Menue$(Row-Min_row+1);CHR$(128);CHR$(136);
1720         DISP "Selection is ";Menue$(Row-Min_row+1);""
1730         Select$=Progr$(Row-Min_row+1)
1740     ELSE
1750         PRINT Menue$(Row-Min_row+1)
1760     END IF
1770 NEXT Row
1780 Row=Min_row
1790 RETURN

```

```

1800 !*****
1810 Move_down: !
1820 CONTROL CRT;Col,Row
1830 PRINT Menu$(Row-Min_row+1);
1840 Row=Row-1
1850 IF Row<Min_row THEN Row=Max_row
1860 CONTROL CRT;Col,Row
1870 PRINT CHR$(129);CHR$(140);Menu$(Row-Min_row+1);CHR$(128);CHR$(136);
1880 DISP "Selection is ";Menu$(Row-Min_row+1);""
1890 Select$=Progr$(Row-Min_row+1)
1900 RETURN
1910 !*****
1920 Move_up: !
1930 CONTROL CRT;Col,Row
1940 PRINT Menu$(Row-Min_row+1);
1950 Row=Row+1
1960 IF Row>Max_row THEN Row=Min_row
1970 CONTROL CRT;Col,Row
1980 PRINT CHR$(129);CHR$(140);Menu$(Row-Min_row+1);CHR$(128);CHR$(136);
1990 DISP "Selection is ";Menu$(Row-Min_row+1);""
2000 Select$=Progr$(Row-Min_row+1)
2010 RETURN
2020 !
2030 !*****
2040 !*****
2050 Get_old_header: ! THIS ROUTINE GETS PREVIOUSLY ENTERED DATA FROM DATA DISK
2060 !
2070 IF Pro_test THEN RETURN
2080 IF New_lot THEN RETURN
2090 !
2100 ENTER @Stat,1;Record$
2110 Record=VAL(Record$)
2120 Rd$=Record$
2130 IF Re<>0 THEN Rd$=Re$
2140 Rd=VAL(Rd$)
2150 ENTER @Data,Rd;Str_in$
2160 Pn_pos=POS(Str_in$,"PN")
2170 Pn_pos=Pn_pos+3
2180 Part_num$=Str_in$(Pn_pos;9)
2190 Ps_pos=POS(Str_in$,"PS")
2200 Ps_pos=Ps_pos+6
2210 Test_spec_num$=Str_in$(Ps_pos;8)
2220 Ln_pos=POS(Str_in$,"LN")
2230 Ln_pos=Ln_pos+3
2240 Lot_num$=Str_in$(Ln_pos;4)
2250 Ds_pos=POS(Str_in$,"DS")
2260 Data_source$=Str_in$(Ds_pos+3;1)
2270 Date_pos=POS(Str_in$,"TD")
2280 Date$=Str_in$(Date_pos+3;8)
2290 Sn_pos=POS(Str_in$,"SN")
2300 Serial_num$=Str_in$(Sn_pos+3;6)
2310 Dm_pos=POS(Str_in$,"DM")

```

```

2320 Date_manuf$=Str_in$[Dm_pos+3;3]
2330 RETURN
2340 !
2350 !*****
2360 !*****
2370 Header_info:! ROUTINE ENTERS HEADER INFORMATION
2380 !
2390 IF NOT (New_lot) THEN RETURN
2400 E_pn: ! ENTERS PART NUMBER
2410 Example$="XXXXXX-XX"
2420 Pos=9
2430 Output$=Part_num$
2440 Item$="PART NUMBER SUFFIX? "
2450 GOSUB Kbd_entry
2460 Part_num$=Output$
2470 IF Re<>0 THEN RETURN
2480 E_ps: ! ENTERS PRODUCT SPECIFICATION NUMBER
2490 Example$="XXXXXX-X"
2500 Pos=9
2510 Item$="TEST SPEC. NUMBER ISSUE"
2520 Output$=Test_spec_num$
2530 GOSUB Kbd_entry
2540 Test_spec_num$=Output$
2550 IF Re<>0 THEN RETURN
2560 !
2570 E_ln: ! ENTERS LOT NUMBER
2580 Example$="XXXX"
2590 Pos=1
2600 Output$=Lot_num$
2610 Item$="LOT NUMBER" ! ENTERS LOT NUMBER
2620 GOSUB Kbd_entry
2630 Lot_num$=Output$
2640 IF Re<>0 THEN RETURN
2650 E_date: ! ENTERS DATE TESTED
2660 Example$="XX-XX-XX"
2670 Pos=1
2680 Output$=Date$
2690 Item$="DATE: (MM-DD-YY)" ! ENTERS DATE
2700 GOSUB Kbd_entry
2710 Date$=Output$
2720 RETURN
2730 !
2740 E_sn:! ENTERS SERIAL NUMBER
2750 Example$="XXXXXX"
2760 Item$="SERIAL NUMBER: " ! INPUT SERIAL NUMBER
2770 IF Re=0 THEN
2780 Output$=""
2790 ELSE
2800 Output$=Serial_num$
2810 END IF
2820 Pos=1
2830 Dum$=KBD$

```

```

2840 GOSUB Kbd_entry
2850 Point=POS(Output$,"X")
2860 Serial_num$=Output$
2870 IF Re<>0 THEN RETURN
2880 E_dm: ! ENTERS DATE MANUFACTURED CODE
2890 Example$="XXX"
2900 IF Re=0 THEN
2910   Output$=""
2920 ELSE
2930   Output$=Date_manuf$
2940 END IF
2950 Pos=1
2960 Item$="DATE MANUFACTURED CODE "
2970 GOSUB Kbd_entry
2980 Date_manuf$=Output$
2990 IF Date_manuf$="KKK" THEN Date_manuf$="  "
3000 IF Re<>0 THEN RETURN
3010 RETURN
3020 !
3030 !*****
3040 !*****
3050 Kbd_entry: ! CONTROLS OPERATOR KEYED INPUTS
3060 Temp=Pos
3070 Exit=No
3080 IF Re<>0 THEN
3090   DISP "MAKE CHANGE TO ";Item$&" THEN DEPRESS ENTER BUTTON"
3100 ELSE
3110   DISP ""
3120   DISP "ENTER > ";Item$&" Depress ENTER button"
3130 END IF
3140 IF LEN(Output$)<1 THEN Output$=Example$
3150 IF LEN(Output$)<>LEN(Example$) THEN Output$=""
3160 Key$=CHR$(255)&CHR$(60)
3170 GOSUB Process_key1
3180 ON KBD GOSUB Process_key
3190 IF Re<>0 THEN OFF KEY
3200 REPEAT
3210 UNTIL Exit
3220 IF POS(Output$,"X") THEN
3230   Output$=Example$
3240   Pos=Temp
3250   GOTO Kbd_entry
3260 END IF
3270 CONTROL CRT,1;15
3280 PRINT "          "
3290 CONTROL CRT,1;16
3300 PRINT "          "
3310 RETURN
3320 !
3330 Process_key:Key$=KBD$
3340 Process_key1:Key_code=NUM(Key$[1;1])
3350 SELECT Key_code

```

```

3360 CASE 45 TO 57
3370   GOSUB Fix_string
3380 CASE 65 TO 90
3390   GOSUB Fix_string
3400 CASE 97 TO 122
3410   GOSUB Fix_string
3420 CASE 255
3430   IF Key$[2;1]=CHR$(60) THEN
3440     Pos=Pos-1
3450     IF Pos<1 THEN Pos=1
3460     Temp$=Example$[Pos;1]
3470     IF Temp$="-" OR Temp$="." THEN Pos=Pos-1
3480     IF Pos<1 THEN Pos=1
3490   END IF
3500   IF Key$[2;1]=CHR$(62) THEN
3510     Pos=Pos+1
3520     Temp$=Example$[Pos;1]
3530     IF Temp$="-" OR Temp$="." THEN Pos=Pos+1
3540     IF Pos=14 THEN Pos=15
3550   END IF
3560   IF Pos>LEN(Example$) THEN Pos=LEN(Example$)
3570   IF Key$[2;1]=CHR$(69) THEN
3580     Exit=Yes
3590   END IF
3600   IF Key$[2;1]=CHR$(67) THEN
3610     Exit=Yes
3620   END IF
3630   IF Key$[2;1]=CHR$(88) THEN
3640     Exit=Yes
3650   END IF
3660 CASE ELSE
3670   Pos=Pos+1
3680   IF Pos>LEN(Example$) THEN Pos=LEN(Example$)
3690 END SELECT
3700 CONTROL CRT,1;15
3710 PRINT Output$
3720 CONTROL CRT,1;16
3730 CONTROL CRT,0;1
3740 PRINT "
3750 CONTROL CRT,1;16
3760 CONTROL CRT,0;Pos
3770 PRINT "^"
3780 RETURN
3790 Fix_string:Output$[Pos;1]=Key$
3800 Pos=Pos+1
3810 Temp$=Example$[Pos;1]
3820 IF Temp$="-" OR Temp$="." THEN Pos=Pos+1
3830 IF Pos>LEN(Example$) THEN Pos=LEN(Example$)
3840 RETURN
3850 !
3860 Question: !
3870 ON KBD GOTO Answer

```



```

3880 CONTROL CRT,1;17
3890 PRINT Item$
3900 Re_loop:DISP "PRESS Y OR N KEY"
3910 WAIT .25
3920 DISP "PRESS OR KEY"
3930 WAIT .25
3940 GOTO Re_loop
3950 Answer:Keyb$=KBD$
3960 IF Keyb$="Y" THEN
3970     OFF KBD
3980     Answer$="Y"
3990     CONTROL CRT,1;17
4000     PRINT USING "50X"
4010     DISP
4020     RETURN
4030 END IF
4040 IF Keyb$="N" THEN
4050     OFF KBD
4060     Answer$="N"
4070     CONTROL CRT,1;17
4080     PRINT USING "50X"
4090     DISP
4100     RETURN
4110 END IF
4120 GOTO Question
4130 !
4140 !*****
4150 !*****
4160 Header_verify:!! GIVES CHANCE TO VERIFY OPERATOR INPUTS
4170 PRINT CHR$(12)
4180 DISP ""
4190 IF NOT (New_lot) THEN GOSUB E_date
4200 CONTROL CRT;10,5
4210 GOSUB Pr_to_printer
4220 Edit_q:ON KBD GOTO Edit_ans
4230 DISP "DO YOU NEED TO EDIT THIS DATA(Y/N)?"
4240 Wait11:GOTO Wait11
4250 Edit_ans:A$=KBD$
4260 IF A$="Y" THEN
4270     IF New_lot THEN
4280         GOSUB Ds_menu
4290         GOSUB Header_info
4300         GOTO Header_verify
4310     END IF
4320     GOSUB Close_file
4330     GOTO Start
4340 END IF
4350 IF A$<>"N" THEN Edit_q
4360 PRINT CHR$(12)
4370 DISP ""
4380 GOSUB E_sn
4390 !*****

```

```

4400 !*****
4410 Test_choice:! GIVES CHOICE TO TEST I.R./TEST CONT./STORE DATA
4420 DISP ""
4430 PRINT CHR$(12)
4440 CONTROL CRT;1,15
4450 PRINT "DO YOU WANT TO TEST CONTINUITY OR INSULATION RESISTANCE?"
4460 OUTPUT KBD USING "#,K";"|"
4470 ON KEY 1 LABEL " CONT." GOTO Cont_sel
4480 ON KEY 2 GOTO Wait
4490 ON KEY 3 GOTO Wait
4500 ON KEY 4 LABEL " I.R." GOTO Ir_sel
4510 ON KEY 5 LABEL " STORE DATA " GOTO Print_out
4520 ON KEY 6 GOTO Wait
4530 ON KEY 7 GOTO Wait
4540 ON KEY 8 LABEL " END TESTING" GOTO End_t
4550 ON KBD GOTO Wait
4560 Wait:GOTO Wait
4570 End_t:OUTPUT KBD USING "#,K";"|"
4580 GOSUB Close_file
4590 GOTO Start
4600 !
4610 !*****
4620 Cont_sel:! GETTING READY TO TEST CONTINUITY
4630 OFF KBD
4640 OUTPUT KBD USING "#,K";"|"
4650 DISP ""
4660 PRINT CHR$(12)
4670 CONTROL CRT;1,15
4680 Disp$="PLACE PART IN CONTINUITY FIXTURE AND PLACE IN SAFETY CHAMBER AND CL
OSE DOOR."
4690 GOSUB Wait_for_key
4700 Cont_sel2:! GIVES CHOICE TO TEST 1 OR ALL CONTINUITY TESTS
4710 OFF KBD
4720 PRINT CHR$(12)
4730 DISP ""
4740 ON KBD GOTO Cont_sel3
4750 Cont_test_num=0
4760 DISP "DO YOU WANT TO AUTOMATICALLY RUN THROUGH ALL THREE(3) CONTINUITY TES
TS?(Y/N)"
4770 Wait3:GOTO Wait3
4780 Cont_sel3:A$=KBD$
4790 OFF KBD
4800 DISP ""
4810 IF A$="Y" THEN Test_cont
4820 IF A$<>"N" THEN Cont_sel2
4830 Man_cont:! PREPARE TO MANUALLY RUN THROUGH CONT. TESTS
4840 INPUT "ENTER CONTINUITY TEST NUMBER (1-3)",Cont_test_num$
4850 IF Cont_test_num$<>"1" THEN
4860 IF Cont_test_num$<>"2" THEN
4870 IF Cont_test_num$<>"3" THEN Man_cont
4880 END IF
4890 END IF

```

```

4900 Cont_test_num=VAL(Cont_test_num$)
4910 GOSUB Test_cont
4920 RETURN
4930 !
4940 !*****
4950 !*****
4960 Ir_sel: ! GETTING READY TO TEST INSULATION RESISTANCE TESTS
4970 OFF KBD
4980 OUTPUT KBD USING "#,K";"|"
4990 DISP ""
5000 PRINT CHR$(12)
5010 CONTROL CRT;1,15
5020 Disp$="PLACE PART IN INSULATION RESISTANCE FIXTURE AND PLACE IN SAFETY CHA
MBER AND      CLOSE DOOR "
5030 GOSUB Wait_for_key
5040 Ir_sel2: ! GIVES CHOICE TO RUN 1 OR ALL INSULATION RESISTANCE TESTS
5050 OFF KBD
5060 PRINT CHR$(12)
5070 DISP ""
5080 ON KBD GOTO Ir_sel3
5090 Ir_test_sel=0
5100 Ir_test_sel$=VAL$(Ir_test_sel)
5110 DISP "DO YOU WANT TO AUTOMATICALLY RUN THROUGH ALL NINE(9) I.R. TESTS?(Y/N
)"
5120 Wait5:GOTO Wait5
5130 Ir_sel3:A$=KBD$
5140 OFF KBD
5150 IF A$="Y" THEN Test_ir
5160 IF A$<>"N" THEN Ir_sel2
5170 Man_ir:! PREPARE TO MANUALLY RUN THROUGH INSULATION RESISTANCE TESTS
5180 INPUT "ENTER I.R. TEST NUMBER (1-9)",Ir_test_sel$
5190 IF Ir_test_sel$<>"1" THEN
5200   IF Ir_test_sel$<>"2" THEN
5210     IF Ir_test_sel$<>"3" THEN
5220       IF Ir_test_sel$<>"4" THEN
5230         IF Ir_test_sel$<>"5" THEN
5240           IF Ir_test_sel$<>"6" THEN
5250             IF Ir_test_sel$<>"7" THEN
5260               IF Ir_test_sel$<>"8" THEN
5270                 IF Ir_test_sel$<>"9" THEN Man_ir
5280                 END IF
5290             END IF
5300           END IF
5310         END IF
5320       END IF
5330     END IF
5340   END IF
5350 END IF
5360 Ir_test_sel=VAL(Ir_test_sel$)
5370 GOSUB Test_ir
5380 RETURN
5390 !*****

```

```

5400 !***** VARIABLES AND LIMITS *****
5410 !*****
5420 Init_test_var: !INITIALIZE VARIABLES FOR DATA
5430      !
5440   FOR I=1 TO 9
5450     Ir_stat$(I)=""
5460   NEXT I
5470   FOR I=1 TO 3
5480     R$(I)=""
5490     R(I)=0
5500   NEXT I
5510   RETURN
5520   !
5530   !*****
5540   Init_const: !
5550     Part_num$=""
5560     Test_spec_num$=""
5570     Lot_num$=""
5580     Date$=""
5590     Serial_num$=""
5600     Date_manuf$=""
5610     !
5620     !***** LIMITS *****
5630     Up_volt_lim(1)=(A+C)/1000
5640     Low_volt_lim(1)=(A-C)/1000
5650     FOR I=2 TO 9
5660       Up_volt_lim(I)=(B+D)/1000
5670       Low_volt_lim(I)=(B-D)/1000
5680     NEXT I
5690     !
5700     !***** LIMITS FOR CONTINUITY *****
5710     R_up$(1)="x.xxxx"
5720     R_low$(1)="y.yyyy"
5730     R_up$(2)="x.xxxx"
5740     R_low$(2)="y.yyyy"
5750     R_up$(3)="x.xxxx"
5760     R_low$(3)="y.yyyy"
5770     !
5780     FOR I=1 TO 3
5790       R_up(I)=VAL(R_up$(I))
5800       R_low(I)=VAL(R_low$(I))
5810     NEXT I
5820     !
5830     !***** VARIALBES *****
5840     Test_code$="AA"
5850     No=0
5860     Yes=1
5870     Door_mon=0 ! BIT=1 IF DOOR IS OPEN
5880     Key_mon=1 ! BIT=0 IF TESTER IS ARMED
5890     Comparator_mon=2 ! BIT=0 IF IR REJECT
5900     Sim_reject=0
5910     RETURN

```

```

5920 !
5930 !*****
5940 !*****
5950 Monitor: ! MONITORS SAFETY CHAMBER DOOR, ARM STATE, COMPARATOR STATE
5960 DISP ""
5970 PRINT CHR$(13)
5980 GOSUB Door_open
5990 GOSUB Arm_tester
6000 GOSUB Reset_ir
6010 RETURN
6020 !*****
6030 !*****
6040 Door_open: ! MAKES SURE SAFETY CHAMBER DOOR IS CLOSED
6050 ENTER @Gpio_14 USING "#,W";Monitor
6060 IF BIT(Monitor,Door_mon)=1 THEN
6070     CONTROL CRT;25,15
6080     PRINT CHR$(130);"***** CLOSE CHAMBER DOOR *****";CHR$(128)
6090     WAIT 3
6100     GOTO Door_open
6110 END IF
6120 PRINT CHR$(12)
6130 RETURN
6140 !*****
6150 !*****
6160 Safe_tester:! MAKES SURE KEY IS IN SAFE POSITION
6170 ENTER @Gpio_14 USING "#,W";Monitor
6180 IF BIT(Monitor,Key_mon)=0 THEN
6190     DISP ""
6200     CONTROL CRT;25,15
6210     PRINT CHR$(130);"***** SAFE TESTER *****";CHR$(128)
6220     WAIT 3
6230     GOTO Safe_tester
6240 END IF
6250 PRINT CHR$(12)
6260 RETURN
6270 !*****
6280 !*****
6290 Arm_tester:! MAKES SURE KEY IS IN ARMED POSITION
6300 ENTER @Gpio_14 USING "#,W";Monitor
6310 IF BIT(Monitor,Key_mon)=1 THEN
6320     CONTROL CRT;25,15
6330     PRINT CHR$(130);"***** ARM TESTER *****";CHR$(128)
6340     WAIT 3
6350     GOTO Arm_tester
6360 END IF
6370 RETURN
6380 !*****
6390 !*****
6400 Reset_ir:! INSTRUCTS TO RESET INSULATION RESISTANCE BUTTON
6410 ENTER @Gpio_14 USING "#,W";Monitor
6420 IF BIT(Monitor,Comparator_mon)=0 THEN
6430     PRINT TABXY(18,8);CHR$(130);"***** INSULATION RESISTANCE FAILURE ON TEST

```

```

";Ir_test_num;" *****";CHR$(128)
6440 PRINT TABXY(25,13);CHR$(130);"***** RESET I.R. BUTTON *****";CHR$(128)
6450 FOR I=1 TO 3
6460 BEEP 500,.5
6470 WAIT .5
6480 NEXT I
6490 GOTO Reset_ir
6500 END IF
6510 RETURN
6520 !*****
6530 !*****
6540 Addressing:
6550 ASSIGN @Volt TO 72300
6560 OUTPUT @Volt;"F1R1"
6570 ASSIGN @Gpio_12 TO 12
6580 ASSIGN @Gpio_14 TO 14
6590 ASSIGN @Keithley TO 72500
6600 RETURN
6610 !
6620 !*****
6630 !***** I.R. TESTING ROUTINE *****
6640 !*****
6650 Test_ir: ROUTINE TO PERFORM I.R. TESTS
6660 LOCAL LOCKOUT 7
6670 !***** RELAYS FOR IR TESTING *****
6680 Volt_to_uut_12(1)=2^0+2^6+2^7+2^10
6690 Volt_to_uut_14(1)=2^14+(-2^15)
6700 Volt_to_uut_12(2)=2^0+2^6
6710 Volt_to_uut_14(2)=2^1+(-2^15)
6720 Volt_to_uut_12(3)=2^0+2^6
6730 Volt_to_uut_14(3)=2^5+(-2^15)
6740 Volt_to_uut_12(4)=2^0+2^6
6750 Volt_to_uut_14(4)=2^1+2^5+2^6
6760 Volt_to_uut_12(5)=2^0+2^6
6770 Volt_to_uut_14(5)=2^0+(-2^15)
6780 Volt_to_uut_12(6)=2^0+2^6
6790 Volt_to_uut_14(6)=2^4+(-2^15)
6800 Volt_to_uut_12(7)=2^0+2^6
6810 Volt_to_uut_14(7)=2^0+2^4+2^6
6820 Volt_to_uut_12(8)=2^0+2^6
6830 Volt_to_uut_14(8)=2^8+(-2^15)
6840 Volt_to_uut_12(9)=2^0+2^6
6850 Volt_to_uut_14(9)=2^7+(-2^15)
6860 !*****
6870 !*****
6880 FOR Ir_test_num=1 TO 9
6890 GOSUB Monitor
6900 DISP ""
6910 PRINT CHR$(12)
6920 CONTROL CRT;20,15
6930 IF Ir_test_sel<>0 THEN Ir_test_num=Ir_test_sel ! FOR MANUAL TEST OF ONE
TEST

```

```

6940   Ir_test_num$=VAL$(Ir_test_num)
6950   PRINT "TESTING SERIAL NUMBER "&Serial_num$
6960   CONTROL CRT;25,17
6970   PRINT " I.R. TEST NUMBER "&Ir_test_num$
6980   !*****
6990   Testing:      !
7000   OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(Ir_test_num)!CLOSE ALL RELAYS
7010   OUTPUT @Gpio_14 USING "#,W";Volt_to_uut_14(Ir_test_num)!EXCEPT TO TURN O
N HIGH VOLT P.S.
7020   IF Ir_test_num=1 THEN
7030       OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(Ir_test_num)+2^13+2^9!TURN
ON VOLT TO HIGH VOLT P.S.(K111,K110)
7040   ELSE
7050       OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(Ir_test_num)+2^13!TURN ON V
OLT TO HIGH VOLT P.S.(K111)
7060   END IF
7070   !
7080   !***** CHECKING VOLTAGE *****
7090   IF Sim_reject=0 THEN
7100   Ck_volt:!VERIFY VOLTAGE WITHIN LIMITS
7110       WAIT 1
7120       OUTPUT @Volt;"F1R1"
7130       ENTER @Volt;Volt$
7140       Volt=VAL(Volt$)
7150       ENTER @Gpio_14 USING "#,W";Monitor
7160       IF Serial_num$<>"SIMULATOR" THEN
7170           IF NOT BIT(Monitor,Comparator_mon) THEN Ir_reject
7180       END IF
7190   !
7200       IF Volt>Up_volt_lim(Ir_test_num) THEN Volt_out_range
7210       IF Volt<Low_volt_lim(Ir_test_num) THEN Volt_out_range
7220   !
7230   END IF
7240   FOR I=1 TO 4
7250       WAIT 1
7260       ENTER @Gpio_14 USING "#,W";Monitor
7270       IF NOT BIT(Monitor,Comparator_mon) THEN Ck_comparator
7280   NEXT I
7290   WAIT 1
7300   !*****
7310   Ck_comparator:  ! CHECKS STATE OF COMPARATOR
7320   OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(Ir_test_num)!TURNS OFF VOLT T
O HIGH VOLT P.S.
7330   WAIT 3
7340   OUTPUT @Gpio_14 USING "#,W";0
7350   WAIT 4
7360   OUTPUT @Gpio_12 USING "#,W";0
7370   !
7380   IF Serial_num$="SIMULATOR" THEN RETURN
7390   ENTER @Gpio_14 USING "#,W";Monitor
7400   IF NOT BIT(Monitor,Comparator_mon) THEN Ir_reject
7410   WAIT 1

```

```

7420 ENTER @Gpio_14 USING "#,W";Monitor
7430 IF NOT BIT(Monitor,Comparator_mon) THEN Ir_reject
7440 Ir_accept: !
7450 Ir_stat$(Ir_test_num)="ACCEPT"
7460 GOTO Ir_end
7470 Ir_reject: !
7480 Ir_stat$(Ir_test_num)="REJECT"
7490 OUTPUT @Gpio_12 USING "#,W";0
7500 OUTPUT @Gpio_14 USING "#,W";0
7510 PRINT CHR$(12)
7520 CONTROL CRT;20,12
7530 GOSUB Reset_ir
7540 IF NOT BIT(Monitor,Comparator_mon) THEN Ir_reject
7550 GOTO Ir_end
7560 !*****
7570 Volt_out_range:! HIGH VOLT SUPPLY(S) OUT OF LIMITS
7580 OUTPUT @Gpio_12 USING "#,W";0 ! CLEARS I/O
7590 OUTPUT @Gpio_14 USING "#,W";0
7600 IF Serial_num$="SIMULATOR" THEN RETURN
7610 PRINT CHR$(12)
7620 Ps$="B VOLT"
7630 IF Ir_test_num=1 THEN Ps$="A VOLT"
7640 CONTROL CRT;20,10
7650 PRINT Ps$&" POWER SUPPLY OUT OF LIMITS "
7660 CONTROL CRT;20,13
7670 PRINT "SAFE TESTER AND NOTIFY AREA FOREMAN"
7680 ON KBD GOTO Start
7690 GOSUB Close_file
7700 DISP "PRESS ANY KEY TO RETURN TO MAIN MENU"
7710 Wait2:GOTO Wait2
7720 Ir_end:!
7730 OUTPUT @Gpio_12 USING "#,W";0 ! CLEARS I/O
7740 OUTPUT @Gpio_14 USING "#,W";0
7750 OUTPUT @Volt;"F1R1"
7760 PRINT CHR$(12)
7770 IF Ir_test_sel<>0 THEN GOSUB Safe_tester
7780 PRINT CHR$(12)
7790 Test_another_ir:!ALLOWS RETEST OR TESTING OF NEXT MANUAL TEST
7800 IF Ir_test_sel<>0 THEN
7810 CONTROL CRT;30,5
7820 PRINT "SERIAL NUMBER "&Serial_num$
7830 CONTROL CRT;25,7
7840 PRINT "I.R. TEST NUMBER "&Ir_test_num$&" "&Ir_stat$(Ir_test_num)
7850 ON KBD GOTO Test_ir_again
7860 DISP "DO YOU WANT TO TEST I.R. AGAIN?(Y/N)"
7870 Wait7:GOTO Wait7
7880 Test_ir_again:A$=KBD$
7890 IF A$="Y" THEN Ir_sel2
7900 IF A$<>"N" THEN Test_another_ir
7910 GOSUB Safe_tester
7920 GOTO Test_choice
7930 END IF

```



```

7940 NEXT Ir_test_num
7950 GOSUB Safe_tester
7960 CONTROL CRT;30,5
7970 PRINT "SERIAL NUMBER "&Serial_num$
7980 FOR I=1 TO 9
7990   I$=VAL$(I)
8000   CONTROL CRT;25,7+I
8010   PRINT "I.R. TEST NUMBER "&I$& " "&Ir_stat$(I)
8020 NEXT I
8030 Retest_ir: ! ALLOWS RETEST IF IN AUTOMATIC TEST MODE
8040 ON KBD GOTO Retest_ir_ans
8050 DISP "DO YOU WANT TO RETEST?(Y/N)"
8060 Wait8:GOTO Wait8
8070 Retest_ir_ans:A$=KBD$
8080 IF A$="Y" THEN Ir_sel2
8090 IF A$<>"N" THEN Retest_ir
8100 GOSUB Safe_tester
8110 GOTO Test_choice
8120 !*****
8130 !***** CONTINUITY TESTING ROUTINE *****
8140 !*****
8150 Test_cont: ! PERFORMS CONTINUITY TESTS
8160 !
8170 GOSUB Monitor
8180 PRINT CHR$(12)
8190 IF Cont_test_num=2 THEN GOTO Cont_2 ! TESTS SELECTED
8200 IF Cont_test_num=3 THEN GOTO Cont_3 ! CONT. TEST IF IN MANUAL MODE
8210 !
8220 Cont_1:OUTPUT @Gpio_12 USING "#,W";2^1+2^3
8230 OUTPUT @Keithley;"R0P0Z0T5G1X"
8240 PRINT CHR$(12)
8250 CONTROL CRT;20,15
8260 PRINT "TESTING SERIAL NUMBER "&Serial_num$
8270 CONTROL CRT;22,17
8280 PRINT "CONTINUITY TEST NUMBER 1"
8290 WAIT 1
8300 ENTER @Keithley;R$(1)
8310 R(1)=VAL(R$(1))
8320 R(1)=INT(R(1)*10^4)/10^4
8330 R$(1)=VAL$(R(1))
8340 FOR I=1 TO 3
8350   IF LEN(R$(1))<6 THEN
8360     R$(1)=R$(1)&"0"
8370   END IF
8380 NEXT I
8390 IF LEN(R$(1))>6 THEN R$(1)=R$(1)[1,6]
8400 IF Cont_test_num<>0 THEN Cont_end
8410 Cont_2:OUTPUT @Gpio_12 USING "#,W";2^1+2^2
8420 OUTPUT @Keithley;"R0P0Z0T5G1X"
8430 PRINT CHR$(12)
8440 CONTROL CRT;20,15
8450 PRINT "TESTING SERIAL NUMBER "&Serial_num$

```

```

8460 CONTROL CRT;22,17
8470 PRINT "CONTINUITY TEST NUMBER 2"
8480 WAIT 1
8490 ENTER @Keithley;R$(2)
8500 R(2)=VAL(R$(2))
8510 R(2)=INT(R(2)*10^4)/10^4
8520 R$(2)=VAL$(R(2))
8530 FOR I=1 TO 6
8540     IF LEN(R$(2))<6 THEN
8550         R$(2)=R$(2)&"0"
8560     END IF
8570 NEXT I
8580 IF LEN(R$(2))>6 THEN R$(2)=R$(2)[1,6]
8590 IF Cont_test_num<>0 THEN Cont_end
8600 Cont_3:OUTPUT @Gpio_12 USING "#,W";2^1+2^11
8610 OUTPUT @Keithley;"R0P0Z0T5G1X"
8620 PRINT CHR$(12)
8630 CONTROL CRT;20,15
8640 PRINT "TESTING SERIAL NUMBER "&Serial_num$
8650 CONTROL CRT;22,17
8660 PRINT "CONTINUITY TEST NUMBER 3"
8670 WAIT 1
8680 ENTER @Keithley;R$(3)
8690 R(3)=VAL(R$(3))
8700 R(3)=INT(R(3)*10^4)/10^4
8710 R$(3)=VAL$(R(3))
8720 FOR I=1 TO 5
8730     IF LEN(R$(3))<5 THEN
8740         R$(3)=R$(3)&"0"
8750     END IF
8760 NEXT I
8770 IF LEN(R$(3))>5 THEN R$(3)=R$(3)[1,5]
8780 Cont_end: !
8790 OUTPUT @Gpio_12 USING "#,W";0
8800 OUTPUT @Gpio_14 USING "#,W";0
8810 PRINT CHR$(12)
8820 !
8830 GOSUB Safe_tester
8840 PRINT CHR$(12)
8850 PRINT TAB(11);"TEST";TAB(29);"LIMITS(OHMS)";TAB(45);"VALUE(ohms)";TAB(60);
"STATUS"
8860 PRINT
8870 IF Cont_test_num<>0 THEN
8880     Cont_stat$(Cont_test_num)="C"
8890     IF R_up(Cont_test_num)<R(Cont_test_num) THEN Cont_stat$(Cont_test_num)="
H"
8900     IF R_low(Cont_test_num)>R(Cont_test_num) THEN Cont_stat$(Cont_test_num)=
"L"
8910     IF Cont_stat$(Cont_test_num)="C" THEN
8920         Cont_ar$(Cont_test_num)="ACCEPT"
8930     ELSE
8940         Cont_ar$(Cont_test_num)="REJECT"

```

```

8950   END IF
8960   C=Cont_test_num
8970   PRINT TAB(5);"CONT. TEST NUMBER ";Cont_test_num$;TAB(27);R_up$(C);TAB(35
);R_low$(C);TAB(47);R$(C);TAB(60);Cont_ar$(C)
8980   ELSE
8990     FOR I=1 TO 3
9000       I$=VAL$(I)
9010       Cont_stat$(I)="C"
9020       IF R_up(I)<R(I) THEN Cont_stat$(I)="H"
9030       IF R_low(I)>R(I) THEN Cont_stat$(I)="L"
9040       IF Cont_stat$(I)="C" THEN
9050         Cont_ar$(I)="ACCEPT"
9060       ELSE
9070         Cont_ar$(I)="REJECT"
9080       END IF
9090       PRINT TAB(5);"CONT TEST NUMBER ";I$;TAB(27);R_up$(I);TAB(35);R_low$(I)
;TAB(47);R$(I);TAB(60);Cont_ar$(I)
9100     NEXT I
9110   END IF
9120   IF Serial_num$="SIMULATOR" THEN RETURN
9130   Test_another_co: ! ALLOWS RETEST OR NEXT MANUAL TEST
9140   ON KBD GOTO Test_co_again
9150   DISP "DO YOU WANT TO RETEST CONTINUITY ?(Y/N)"
9160   Wait9:GOTO Wait9
9170   Test_co_again:A$=KBD$
9180   IF A$="Y" THEN Cont_sel2
9190   IF A$<>"N" THEN Test_another_co
9200   GOSUB Safe_tester
9210   GOTO Test_choice
9220   !
9230   !*****
9240   !*****
9250   Data_disk: ! SETS UP DATA DISK IN DRIVE 1
9260   IF Pro_test THEN RETURN
9270   ON ERROR GOTO Dk_eras
9280   GOSUB Init_disk
9290   IF NOT (New_lot) THEN Old_data_disk
9300   New_data_disk: !
9310   CREATE BDAT "DATA:,700,1",400,350
9320   CREATE BDAT "STAT:,700,1",20,80
9330   !
9340   !*****
9350   Old_data_disk: !
9360   ASSIGN @Data TO "DATA:,700,1";FORMAT ON
9370   ASSIGN @Stat TO "STAT:,700,1";FORMAT ON
9380   !
9390   GOSUB Get_old_header
9400   RETURN
9410   !
9420   !*****
9430   !*****
9440   Init_disk: !

```

```

9450 ! THIS PROGRAM INITIALIZES A BRAND NEW DISK OR ERASES AN EXISTING DISK
9460 !
9470 PRINT CHR$(12)
9480 GCLEAR
9490 DISP "CHECKING DISK IN DRIVE 1"
9500 ON ERROR GOTO Dk_eras
9510 PRINT CHR$(12)
9520 CAT ":HP,700,1";COUNT Entries
9530 DISP ""
9540 IF NOT (New_lot) THEN RETURN
9550 IF New_lot THEN Loop
9560 GOTO Key_press_1
9570 Loop:Pos=1
9580 Output$=""
9590 INPUT "DO YOU WANT TO ERASE THIS DISK? (type 'YES' then depress ENTER butt
on to erase)",A$
9600 IF A$<>"YES" THEN Key_press_1
9610 OFF KBD
9620 PRINT CHR$(12)
9630 DISP "ERASING DISK IN DRIVE 1"
9640 GOTO Eras
9650 Key_press_1:PRINT CHR$(12)
9660 DISP "INSERT DATA DISK INTO DRIVE 1"
9670 GOSUB Wait_for_key
9680 GOTO Init_disk
9690 Dk_eras:OFF ERROR
9700 DISP "CHECKING DISK"
9710 PRINT CHR$(12)
9720 IF ERRN=85 THEN
9730     GOTO Eras
9740 ELSE
9750     IF ERRN=80 THEN
9760         IF NOT (New_lot) THEN
9770             Disp$="Insert data disk into drive 1"
9780             GOSUB Wait_for_key
9790             RETURN
9800         END IF
9810         GOSUB Wait_for_key
9820         GOTO Init_disk
9830     END IF
9840     PRINT CHR$(12)
9850     Disp$="DISK ERROR--PLEASE CHECK DISK"
9860     GOSUB Wait_for_key
9870     PRINT CHR$(12)
9880     DISP ""
9890     GOTO Init_disk
9900 END IF
9910 Eras: !*****
9920 ON ERROR GOTO Dk_eras
9930 DISP ""
9940 PRINT CHR$(12)
9950 CONTROL 1;1,15

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```

9960 Dr$=VAL$(Dr)
9970 PRINT "DISK IN DRIVE 1 IS BEING INITIALIZED"
9980 INITIALIZE ":HP9122,700,1",0,4
9990 CONTROL 1;1,15
10000 PRINT USING "50X"
10010 OFF ERROR
10020 RETURN
10030 !
10040 Wait_for_key:*****
10050 ON KBD GOTO Exit1
10060 CONTROL 1;1,18
10070 PRINT Disp$
10080 Wait_loop1:DISP "Press ANY KEY when ready."
10090 WAIT .25
10100 DISP
10110 WAIT .25
10120 GOTO Wait_loop1
10130 Exit1:OFF KBD
10140 DISP
10150 CONTROL 1;1,18
10160 PRINT USING "50X"
10170 Disp$=""
10180 OFF ERROR
10190 RETURN
10200 !
10210 !*****
10220 !*****
10230 Print_out:! PRINTS OUT TESTED DATA IN TABLE FORM TO CRT AND PRINTER
10240 IF Printer=0 THEN
10250     OUTPUT KBD USING "#,K","|"
10260     PRINT CHR$(12)
10270 END IF
10280 PRINT TAB(1);"SERIAL NUMBER: "&Serial_num$;TAB(38);"DATE MANUFACTURE CODE:
    ";Date_manuf$
10290 PRINT
10300 OUTPUT 701 USING "#,K",""          !SET PRINTER FOR UNDERLINING
10310 PRINT CHR$(132);TAB(11);"TEST";TAB(29);"Limits(Ohms)";TAB(45);"VALUE(ohms)
    ";TAB(60);"STATUS";CHR$(128)
10320 OUTPUT 701 USING "#,K",""          !TURN OFF UNDERLINING
10330 !
10340 FOR I=1 TO 3
10350     I$=VAL$(I)
10360     PRINT TAB(5);"CONT TEST NUMBER ";I$;TAB(27);R_up$(I);TAB(35);R_low$(I);T
    AB(45);R$(I);TAB(60);Cont_ar$(I)
10370 NEXT I
10380 FOR I=1 TO 9
10390     I$=VAL$(I)
10400     PRINT TAB(5);"I.R. TEST NUMBER "&I$;TAB(60);Ir_stat$(I)
10410 NEXT I
10420 IF Printer=1 THEN RETURN
10430     !
10440 Store_q:          ! VERIFYS ALL TESTS PERFORMED

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```

10450 ON KBD GOTO Store_ans
10460 DISP "ARE YOU READY TO STORE THIS DATA?(Y/N)"
10470 Wait10:GOTO Wait10
10480 Store_ans:A$=KBD$
10490 IF Serial_num$<>"SIMULATOR" THEN
10500   IF A$="N" THEN Test_choice
10510 END IF
10520 IF A$<>"Y" THEN Store_q
10530 FOR I=1 TO 3
10540   IF R$(I)="" THEN Not_all_tested
10550 NEXT I
10560 FOR I=1 TO 9
10570   IF Ir_stat$(I)="" THEN Not_all_tested
10580 NEXT I
10590 PRINTER IS 701
10600 Printer=1
10610 OUTPUT 701 USING "#,K";CHR$(27)&"(s5hu6B"      ! PRINT EXPANDED CHARACTERS
10620 Pr_to_printer:!PRINTS DATA ON PRINTER
10630 PRINT
10640 PRINT
10650 PRINT TAB(16);"ANTS"
10660 PRINT TAB(1);"CONTINUITY/INSULATION RESISTANCE TESTER"
10670 PRINT
10680 OUTPUT 701 USING "#,K";CHR$(27)&"(s10huB"      !PRINT NORMAL SIZE
10690 PRINT "PROCUCT SPECIFICATION: ";Test_spec_num$;TAB(38);"SOFTWARE: ";Am$
10700 PRINT "PART NUMBER: ";Part_num$;TAB(38);"DATE: ";Date$
10710 PRINT "LOT NUMBER: ";Lot_num$;TAB(38);"TEST CODE: ";Test_code$
10720 PRINT TAB(38);"DATA SOURCE CODE: ";Data_source$
10730 PRINT
10740 IF Printer=0 THEN RETURN
10750 GOSUB Print_out
10760 PRINTER IS CRT
10770 Printer=0
10780 !
10790 !*****
10800 !*****
10810 Store_on_disk:!STORES DATA ON DATA DISK ON DRIVE 1
10820 !
10830 IF Serial_num$="SIMULATOR" THEN RETURN
10840 IF Pro_test THEN End_store
10850 Record=Record+1
10860 Record$=VAL$(Record)
10870 OUTPUT @Stat,1;Record$
10880 !
10890 Str1$="H, ID TRANSD, TD "&Date$&", DS "&Data_source$&", PN "&Part_num$&",
MF MAD, TC "&Test_code$&", PS PS-"&Test_spec_num$&", LN "&Lot_num$
10900 Str2$=" , TE ANTS, $T, ID TRANSD, SN "&Serial_num$&", DM "&Date_manuf$&", C
R1 "&R$(1)&Cont_stat$(1)&", CR2 "&R$(2)&Cont_stat$(2)
10910 Str3$=" , CR3 "&R$(3)&Cont_stat$(3)
10920 Str4$=" , IR1 "&Ir_stat$(1)[1,1]&", IR2 "&Ir_stat$(2)[1,1]&", IR3 "&Ir_stat
$(3)[1,1]&", IR4 "&Ir_stat$(4)[1,1]&", IR5 "&Ir_stat$(5)[1,1]
10930 Str5$=" , IR6 "&Ir_stat$(6)[1,1]&", IR7 "&Ir_stat$(7)[1,1]&", IR8 "&Ir_stat

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$(8)[1,1]&" , IR9 "&Ir_stat$(9)[1,1]&" , $"
10940 Str$=Str1$&Str2$&Str3$&Str4$&Str5$
10950 !
10960 OUTPUT @Data,Record;Str$
10970 !
10980 End_store:~
10990 PRINT CHR$(12)
11000 DISP ""
11010 Next_sn_q:ON KBD GOTO Next_sn_a
11020 DISP "DO YOU WANT TO TEST NEXT SERIAL NUMBER?(Y/N)"
11030 Wait14:GOTO Wait14
11040 Next_sn_a:A$=KBD$
11050 IF A$="N" THEN
11060   GOSUB Close_file
11070   GOTO Start
11080 END IF
11090 IF A$<>"Y" THEN Next_sn_q
11100 GOSUB Init_test_var
11110 GOSUB E_sn
11120 GOTO Test_choice
11130 !
11140 !*****
11150 Not_all_tested:~ NOT ALL TESTS PERFORMED
11160 PRINT
11170 Disp$="NOT ALL TESTS HAVE BEEN PERFORMED"
11180 GOSUB Wait_for_key
11190 GOTO Test_choice
11200 !
11210 !*****
11220 !*****
11230 Print_data:~ THIS ROUTINE PRINTS OUT GEISHA DATA FROM THE DATA DISK
11240   !
11250 ON ERROR GOTO Dk_eras2
11260 GOSUB Old_data_disk
11270 DISP TAB(25);"***** PRINTING DATA *****"
11280 PRINTER IS 701
11290 ENTER @Stat,1;Record$
11300 Record=VAL(Record$)
11310 IF Record=1 THEN
11320   ENTER @Data,1;Data$
11330   PRINT Data$
11340 ELSE
11350   FOR I=1 TO Record
11360     ENTER @Data,I;Data$
11370     PRINT Data$
11380   NEXT I
11390 END IF
11400 PRINTER IS CRT
11410 GOSUB Close_file
11420 GOTO Main_menu
11430 !
11440 Dk_eras2:OFF ERROR

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```

11450 IF ERRN=80 THEN DISP "INSERT DATA DISK INTO DRIVE 1"
11460 WAIT 2
11470 GOTO Print_data
11480      !
11490 !
11500 !*****
11510 !*****
11520 Edit_data:! THIS ROUTINE EDITS THE DATA DISK
11530      !
11540 In:INPUT "ENTER RECORD NUMBER TO EDITED ",Re
11550 Re$=VAL$(Re)
11560 ON ERROR GOTO No_record
11570 GOTO Edit_rec
11580 No_record:      !
11590 OFF ERROR
11600 DISP "RECORD "&Re$&" DOES NOT EXIST"
11610 WAIT 2
11620 GOSUB Close_file
11630 GOTO Start
11640 Edit_rec:      !
11650 Edit_menu:!
11660 GOSUB Old_data_disk
11670 Name$="***** EDIT MENU *****"
11680 DATA " DATA SOURCE CODE "
11690 DATA "DS"
11700 DATA " PART NUMBER "
11710 DATA "PN"
11720 DATA " TEST SPECIFICATION NUMBER "
11730 DATA "PS"
11740 DATA " LOT NUMBER "
11750 DATA "LN"
11760 DATA " DATE "
11770 DATA "DATE"
11780 DATA " SERIAL NUMBER "
11790 DATA "SN"
11800 DATA " DATE MANUFACTURE CODE "
11810 DATA "DM"
11820 RESTORE 11670
11830 Menu_items=7
11840 GOSUB Menu
11850 OUTPUT KBD USING "#,K";"|"
11860 ON KEY 1 LABEL "UP" GOSUB Move_down
11870 ON KEY 2 LABEL "DOWN" GOSUB Move_up
11880 ON KEY 3 GOTO Loop_d
11890 ON KEY 4 LABEL "SELECT" GOTO Selectc
11900 ON KEY 5 LABEL " END EDITING" GOTO End_edit
11910 ON KEY 6 GOTO Loop_d
11920 ON KEY 7 GOTO Loop_d
11930 ON KEY 8 LABEL "DELETE" GOTO Delete
11940 ON KBD GOTO Loop_d
11950 Loop_d:GOTO Loop_d
11960 Selectc:OFF KEY

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11970 OUTPUT KBD USING "#,K";"|"
11980 OFF KBD
11990 PRINT CHR$(12)
12000 Edit_select$=Select$
12010 IF Select$="DS" THEN GOSUB Ds_menu
12020 IF Select$="PN" THEN GOSUB E_pn
12030 IF Select$="PS" THEN GOSUB E_ps
12040 IF Select$="LN" THEN GOSUB E_ln
12050 IF Select$="DATE" THEN GOSUB E_date
12060 IF Select$="SN" THEN GOSUB E_sn
12070 IF Select$="DM" THEN GOSUB E_dm
12080 P_output:CONTROL CRT,1;15
12090 PRINT Output$
12100 Item$="IS THIS CHANGE CORRECT?"
12110 GOSUB Question
12120 IF Answer$="N" THEN 12010
12130 IF Answer$<>"Y" THEN P_output
12140 Store:DISP CHR$(12)
12150 Te_pos=POS(Str_in$,"TE")
12160 Te_pos=Te_pos-2
12170 !
12180 IF Edit_select$="SN" THEN Change_individ
12190 IF Edit_select$="DM" THEN Change_individ
12200 IF Edit_select$="DATE" THEN Change_individ
12210 Change_individ:Str_out$=Str_in$[1,Date_pos+2]&Date$&Str_in$[Date_pos+11,Sn_pos+2]&Serial_num$&Str_in$[Sn_pos+9,Dm_pos+2]&Date_manuf$&Str_in$[Dm_pos+6]
12220 OUTPUT @Data,Re;Str_out$
12230 !
12240 IF Edit_select$="DS" THEN Change_common
12250 IF Edit_select$="PN" THEN Change_common
12260 IF Edit_select$="PS" THEN Change_common
12270 IF Edit_select$="LN" THEN Change_common
12280 Change_common:FOR I=1 TO Record
12290 ENTER @Data,I;Str_in$
12300 IF Str_in$="" THEN
12310 I=I+1
12320 GOTO 12290
12330 END IF
12340 Str_out$=Str_in$[1,30]&Data_source$&, PN "&Part_num$&", MF MAD, TC "&Test_code$&", PS PS-"&Test_spec_num$&", LN "&Lot_num$&Str_in$[Te_pos]
12350 OUTPUT @Data,I;Str_out$
12360 NEXT I
12370 GOSUB Close_file
12380 GOTO Edit_menu
12390 End_edit:~
12400 GOSUB Close_file
12410 Re=0
12420 OUTPUT KBD USING "#,K";"|"
12430 GOTO Start
12440 !
12450 Delete:~ DELETES A RECORD FROM THE DATA DISK
12460 OUTPUT KBD USING "#,K";"|"

```

```

12470 PRINT CHR$(12)
12480 Re$=VAL$(Re)
12490 Item$="DELETE RECORD "&Re$&" ?"
12500 GOSUB Question
12510 IF Answer$="N" THEN Edit_menu
12520 IF Answer$<>"Y" THEN Delete
12530 Str_out$=""
12540 DISP "DELETING RECORD "&Re$
12550 OUTPUT @Data,Re;Str_out$
12560 IF Re$=Record$ THEN
12570   Record=Record-1
12580   Record$=VAL$(Record)
12590   OUTPUT @Stat,1;Record$
12600 END IF
12610 GOSUB Close_file
12620 WAIT 3
12630 GOTO Start
12640 Close_file:
12650 ASSIGN @Stat TO *
12660 ASSIGN @Data TO *
12670 RETURN
12680 !
12690 !*****
12700 !*****
12710 Simulator_ck: !VERIFYS SIMULATORS
12720 PRINT CHR$(12)
12730 Continuity_sim: !
12740 !
12750 PRINT CHR$(12)
12760 DISP ""
12770 MOVE 22,70
12780 CSIZE 8,.4
12790 LABEL "VERIFYING CONTINUITY SIMULATOR"
12800 PRINT TABXY(8,10);"   PLACE CONTINUITY SIMULATOR IN CONTINUITY SIDE OF F
IXTURE"
12810 GOSUB Wait_for_key
12820 Serial_num$="SIMULATOR"
12830 GOSUB Test_cont
12840 !
12850 ON KBD GOTO Cont_sim_again
12860 DISP "DO YOU NEED TO RUN THE CONTINUITY SIMULATOR AGAIN(Y/N)?"
12870 Wait1:GOTO Wait1
12880 Cont_sim_again: !
12890 Cs$=KBD$
12900 IF Cs$="Y" THEN Continuity_sim
12910 IF Cs$<>"N" THEN 12850
12920 Ir_sim_ck: !
12930 PRINT CHR$(12)
12940 PRINT TABXY(8,10);"PLACE INSUL. R. SIMULATOR IN INSUL. R. SIDE OF FIXTURE"
12950 GOSUB Wait_for_key
12960 Ck_test=1
12970 Ck_test$="1"

```

```

12980 Sw_pos$="1"
12990 GOSUB Ck_accept
13000 Ck_test=8
13010 Ck_test$="8"
13020 Sw_pos$="2"
13030 GOSUB Ck_accept
13040 Ck_test=9
13050 Ck_test$="9"
13060 Sw_pos$="3"
13070 GOSUB Ck_accept
13080 Ck_test=2
13090 Ck_test$="2"
13100 Sw_pos$="4"
13110 GOSUB Ck_accept
13120 Ck_test=3
13130 Ck_test$="3"
13140 Sw_pos$="5"
13150 GOSUB Ck_accept
13160 Ck_test=5
13170 Ck_test$="5"
13180 Sw_pos$="6"
13190 GOSUB Ck_accept
13200 Ck_test=6
13210 Ck_test$="6"
13220 Sw_pos$="7"
13230 GOSUB Ck_accept
13240 Ck_test=4
13250 Ck_test$="4"
13260 Sw_pos$="8"
13270 GOSUB Ck_accept
13280 Ck_test=7
13290 Ck_test$="7"
13300 Sw_pos$="8"
13310 GOSUB Ck_accept
13320 GOTO Print_sim
13330 Ck_accept:
13340 Ir_test_sel=Ck_test
13350 PRINT CHR$(12)
13360 PRINT TABXY(8,10);"VERIFYING INSUL. RES. SIMULATOR TEST "&Ck_test$
13370 Disp1$="ON INSUL .R. SIMULATOR BOX, MOVE SWITCHES TO POSITION "&Sw_pos$&"
AND ACCEPT"
13380 PRINT TABXY(8,11);Disp1$
13390 GOSUB Wait_for_key
13400 PRINT CHR$(12)
13410 GOSUB Test_ir
13420 !
13430 ENTER @Gpio_14 USING "#,W";Monitor
13440 IF NOT BIT(Monitor,Comparator_mon) THEN Sim_fail
13450 PRINT CHR$(12)
13460 GOSUB Safe_tester
13470 !
13480 Ck_reject:Sim_reject=1

```

```

13490 PRINT CHR$(12)
13500 PRINT TABXY(8,10);"VERIFYING INSUL. RES. SIMULATOR TEST "&Ck_test$
13510 Disp1$="ON INSUL. R. SIMULATOR BOX, MOVE SWITCHES TO POSITION "&Sw_pos$&"
AND REJECT"
13520 PRINT TABXY(8,11);Disp1$
13530 GOSUB Wait_for_key
13540 GOSUB Test_ir
13550 OUTPUT @Gpio_14 USING "#,W";0
13560 OUTPUT @Gpio_12 USING "#,W";0
13570 !
13580 Sim_reject=0
13590 ENTER @Gpio_14 USING "#,W";Monitor !CHECKS STATE OF COMPARATOR
13600 IF BIT(Monitor,Comparator_mon) THEN Sim_fail
13610 PRINT CHR$(12)
13620 GOSUB Safe_tester
13630 ENTER @Gpio_14 USING "#,W";Monitor
13640 IF BIT(Monitor,Comparator_mon)=0 THEN
13650   CONTROL CRT;20,15
13660   PRINT " ***** RESET I.R. BUTTON ***** "
13670   WAIT 3
13680   GOTO 13630
13690 END IF
13700 RETURN
13710 Print_sim:!
13720 FOR I=1 TO 9
13730   Ir_stat$(I)="PASSED"
13740 NEXT I
13750 GOSUB Print_out
13760 Ir_test_sel=0
13770 GOTO Main_menu
13780 !
13790 Sim_fail:!
13800 PRINT CHR$(12)
13810 CONTROL CRT;25,15
13820 PRINT "***** SIMULATOR FAILURE *****"
13830 BEEP 500,.5
13840 WAIT .5
13850 BEEP 500,.5
13860 PRINT CHR$(12)
13870 GOSUB Safe_tester
13880 GOSUB Reset_ir
13890 PRINT CHR$(12)
13900 MOVE 22,70
13910 PRINT TABXY(8,10);"SIMULATOR FAILURE. CHECK SWITCH POSITIONS ON SIMULATOR
BOX"
13920 PRINT TABXY(8,11);Disp1$
13930 ON KBD GOTO Ck_again
13940 DISP "DO YOU NEED TO CHECK THIS POSITION AGAIN (Y/N)?"
13950 Wait6:GOTO Wait6
13960 Ck_again:Ck$=KBD$
13970 IF Ck$="Y" THEN
13980   IF Disp1$[61,66]="REJECT" THEN Ck_reject

```

```
13990 GOTO Ck_accept
14000 END IF
14010 IF Ck$<>"N" THEN Wait6
14020 PRINT CHR$(12)
14030 DISP ""
14040 CONTROL CRT;30,12
14050 PRINT "NOTIFY MAINTENANCE"
14060 GOTO End
14070 End:END
```

APPENDIX D
SELECTED CALIBRATION SOFTWARE LISTING

```

200 !*****
210 !*****
220 Intro_screen: ! DISPLAYS INTRO SCREEN
230 DISP
240 PRINT CHR$(12)
250 GRAPHICS ON
260 GCLEAR
270 MOVE 22,70
280 CSIZE 30,.5
290 LABEL "ANTS"
300 CSIZE 8,.4
310 MOVE 2,65
320 LABEL "CONTINUITY-INSULATION RESISTANCE TESTER"
330 MOVE 36,55
340 LABEL "CALIBRATION PROGRAM"
350 MOVE 44,45
360 LABEL Am$
370 DISP "Press ANY key when ready"
380 ON KBD GOTO Set_up
390 Loop_a:GOTO Loop_a
400 !*****
410 !*****
420 Set_up: !
430 GCLEAR
440 LOCAL LOCKOUT 7
450 ! RELAYS FOR IR TESTING
460 !
470 Volt_to_uut_12(1)=2^0+2^6+2^7+2^10
480 Volt_to_uut_14(1)=2^14+(-2^15)
490 Volt_to_uut_12(2)=2^0+2^6
500 Volt_to_uut_14(2)=2^1+(-2^15)
510 Volt_to_uut_12(3)=2^0+2^6
520 Volt_to_uut_14(3)=2^5+(-2^15)
530 Volt_to_uut_12(4)=2^0+2^6
540 Volt_to_uut_14(4)=2^1+2^5+2^6
550 Volt_to_uut_12(5)=2^0+2^6
560 Volt_to_uut_14(5)=2^0+(-2^15)
570 Volt_to_uut_12(6)=2^0+2^6
580 Volt_to_uut_14(6)=2^4+(-2^15)
590 Volt_to_uut_12(7)=2^0+2^6
600 Volt_to_uut_14(7)=2^0+2^4+2^6
610 Volt_to_uut_12(8)=2^0+2^6
620 Volt_to_uut_14(8)=2^8+(-2^15)
630 Volt_to_uut_12(9)=2^0+2^6
640 Volt_to_uut_14(9)=2^7+(-2^15)
650 Door_mon=0
660 Key_mon=1
670 Comparator_mon=2
680 !*****
690 !*****
700 Addressing: !
710 ASSIGN @Volt TO 72300

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```

720 OUTPUT @Volt;"F1R1"
730 ASSIGN @Gpio_12 TO 12
740 ASSIGN @Gpio_14 TO 14
750 ASSIGN @Keithley TO 72500
760 !*****
770 !*****
780 As_found_val:      !VERIFIES "AS FOUND" VALUES
790 PRINT CHR$(12)
800 Label$="AS FOUND HIGH VOLTAGE P.S."
810 Disp1$="CONNECT STANDARD VOLT METER ACROSS TP101 AND TP102 (TP102 GROUND)"
820 Disp2$="BEHIND CAL. DOOR"
830 Dips3$=""
840 GOSUB Wait_for_key
850 As_found_b_volt: !
860 GOSUB Door_open
870 GOSUB Arm_tester
880 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(2)
890 OUTPUT @Gpio_14 USING "#,W";Volt_to_uut_14(2)
900 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(2)+2^13
910 PRINT CHR$(12)
920 Label$=" AS FOUND B VOLT P.S."
930 Disp1$="(CP17) RECORD READING ON STD. METER 'AS FOUND'"
940 Disp2$=" SHOULD BE (B VOLT) +/- (D VOLT)"
950 Disp3$="(CP19) VERIFY HP3478A DVM IS (CP17)/1000 +/- .000D V"
960 GOSUB Wait_for_key
970 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(2)
980 WAIT 3
990 OUTPUT @Gpio_14 USING "#,W";0
1000 WAIT 4
1010 OUTPUT @Gpio_12 USING "#,W";0
1020 GOSUB Reset_ir
1030 As_found_a_v:!
1040 GOSUB Door_open
1050 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(1)
1060 OUTPUT @Gpio_14 USING "#,W";Volt_to_uut_14(1)
1070 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(1)+2^13+2^9
1080 PRINT CHR$(12)
1090 Label$=" AS FOUND A VOLT P.S."
1100 Disp1$="(CP18) RECORD THIS READING 'AS FOUND'"
1110 Disp2$=" SHOULD BE (A VOLT)+/(C VOLT)"
1120 Disp3$="(CP20) VERIFY HP3478A DVM IS (CP18)/1000 +/- .000C V"
1130 GOSUB Wait_for_key
1140 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(1)
1150 WAIT 3
1160 OUTPUT @Gpio_14 USING "#,W";0
1170 WAIT 4
1180 OUTPUT @Gpio_12 USING "#,W";0
1190 GOSUB Safe_tester
1200 GOSUB Reset_ir
1210 !
1220 Label$=""
1230 Disp1$=" REMOVE STANDARD VOLTMETER"

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1240 Disp2$=""
1250 Disp3$=""
1260 GOSUB Wait_for_key
1270 !*****
1280 !*****
1290 Calibrate: ! SOFTWARE AIDED CALIBRATION
1300 Cal_com_1: ! TRIP AT bb.b MICROAMPS
1310 Label$="CALIBRATING THE COMPARATORS"
1320 Disp1$="PLACE I.R. SIMULATOR IN I.R. FIXTURE AND CLOSE BARRICADE DOOR."
1330 Disp2$="ON SIMULATOR BOX, POSITION SWITCHES ON POS. 2 AND REJECT"
1340 Disp3$="REMOVE SHORTING PLUG(TP104) IN CAL DOOR AND PLUG IN STANDARD
      AMMETER(B GROUND)"
1350 GOSUB Wait_for_key
1360 GOSUB Arm_tester
1370 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(8)
1380 OUTPUT @Gpio_14 USING "#,W";Volt_to_uut_14(8)
1390 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(8)+2^13
1400 PRINT CHR$(12)
1410 Label$="CALIBRATING COMPARATOR 1"
1420 Disp1$="ADJUST COMPARATOR 1 UNTIL REJECT LIGHT STAYS OFF"
1430 Disp2$="ADJUST B VOLT P.S. UNTIL STD. AMMETER READS (bb.b-2) +/- 1 MICROAM
PS"
1440 Disp3$="ADJUST COMPARATOR 1 JUST UNTIL IT TRIPS(REJECT LAMP WILL LIGHT)"
1450 GOSUB Wait_for_key
1460 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(2)
1470 WAIT 3
1480 OUTPUT @Gpio_14 USING "#,W";0
1490 OUTPUT @Gpio_12 USING "#,W";0
1500 GOSUB Reset_ir
1510 GOSUB Safe_tester
1520 PRINT CHR$(12)
1530 Label$=""
1540 Disp1$="POSITION SWITCH ON SIMULATOR BOX TO POS. 1 AND REJECT"
1550 Disp2$=""
1560 Disp3$=""
1570 GOSUB Wait_for_key
1580 !
1590 Cal_com_2:! TRIP AT aa.a MICROAMPS
1600 GOSUB Door_open
1610 GOSUB Arm_tester
1620 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(1)
1630 OUTPUT @Gpio_14 USING "#,W";Volt_to_uut_14(1)
1640 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(1)+2^13+2^9
1650 PRINT CHR$(12)
1660 Label$="CALIBRATING COMPARATOR 2"
1670 Disp1$="ADJUST COMPARATOR 2 UNTIL REJECT LIGHT STAYS OFF"
1680 Disp2$="ADJUST A VOLT P.S. UNTIL STD. AMMETER READS (aa.a-3)+/-2 MICROAMPS
"
1690 Disp3$="ADJUST COMPARATOR 2 JUST UNTIL IT TRIPS(REJECT LAMP WILL LIGHT)"
1700 GOSUB Wait_for_key
1710 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(1)
1720 WAIT 3

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1730 OUTPUT @Gpio_14 USING "#,W";0
1740 OUTPUT @Gpio_12 USING "#,W";0
1750 GOSUB Safe_tester
1760 GOSUB Reset_ir
1770 !*****
1780 Cal_ps:      !
1790 PRINT CHR$(12)
1800 Label$="CALIBRATING B VOLT P.S."
1810 Disp1$="POSITION SWITCH ON SIMULATOR BOX TO ACCEPT"
1820 Disp2$="REPLACE SHORTING PLUG IN TP104"
1830 Disp3$="CONNECT STANDARD VOLT METER ACROSS TP101 AND TP102 (TP102 GROUND)"
1840 GOSUB Wait_for_key
1850 Cal_b_v_ps:GOSUB Door_open
1860 GOSUB Arm_tester
1870 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(2)
1880 OUTPUT @Gpio_14 USING "#,W";Volt_to_uut_14(2)
1890 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(2)+2^13
1900 PRINT CHR$(12)
1910 Disp1$="(CP17) ADJUST B VOLT P.S. UNTIL STD. VOLTMETER READS (B VOLT) +/-
(D/10)V"
1920 Disp2$="(CP19) VERIFY HP3478A DVM IS (CP17)/1000 +/- .0000D V"
1930 Disp3$="      IF NOT, NOTIFY MAINTENANCE"
1940 GOSUB Wait_for_key
1950 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(2)
1960 WAIT 3
1970 OUTPUT @Gpio_14 USING "#,W";0
1980 WAIT 4
1990 OUTPUT @Gpio_12 USING "#,W";0
2000 GOSUB Reset_ir
2010 Cal_a_v_ps:GOSUB Door_open
2020 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(1)
2030 OUTPUT @Gpio_14 USING "#,W";Volt_to_uut_14(1)
2040 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(1)+2^13+2^9
2050 PRINT CHR$(12)
2060 Label$="CALIBRATING A VOLT P.S."
2070 Disp1$="(CP18) ADJUST A VOLT P.S. UNTIL STD. VOLTMETER READS (A VOLT) +/-
(C/10)V"
2080 Disp2$="(CP20) VERIFY HP3478A DVM IS (CP18)/1000 +/- .0000C V"
2090 Disp3$="      IF NOT, NOTIFY MAINTENANCE"
2100 GOSUB Wait_for_key
2110 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(1)
2120 WAIT 3
2130 OUTPUT @Gpio_14 USING "#,W";0
2140 WAIT 4
2150 OUTPUT @Gpio_12 USING "#,W";0
2160 GOSUB Safe_tester
2170 GOSUB Reset_ir
2180 !*****
2190 Verify_timing: !
2200 Label$="VERIFYING REQUIRED TIME INTERVAL"
2210 Disp1$=" CONNECT THE STORAGE SCOPE ACROSS TP102 AND TP103 (TP102 GROUND)"
2220 Disp2$=" SWITCH INSULATION RESISTANCE BOX TO ACCEPT AND POS. 2"

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2230 Disp3$=" CHECK TIMING OF B/1000 VOLT SIGNAL"
2240 GOSUB Wait_for_key
2250 GOSUB Door_open
2260 GOSUB Arm_tester
2270 PRINT CHR$(12)
2280 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(2)
2290 OUTPUT @Gpio_14 USING "#,W";Volt_to_uut_14(2)
2300 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(2)+2^13
2310 !***** MOST OF THE FOLLOWING LINES ARE USED TO IMITATE THE TIMING DURING
        TESTING *****
2320 WAIT 1
2330 ENTER @Volt;Volt$
2340 Volt=VAL(Volt$)
2350 ENTER @Gpio_14 USING "#,W";Monitor
2360 IF Imitate_t=Imitate_t THEN
2370     IF NOT BIT(Monitor,Comparator_mon) THEN 2380
2380 END IF
2390 IF 0>1 THEN Volt_out_range
2400 IF 1<0 THEN Volt_out_range
2410 FOR I=1 TO 4
2420     WAIT 1
2430     ENTER @Gpio_14 USING "#,W";Monitor
2440     IF NOT BIT(Monitor,Comparator_mon) THEN 2450
2450 NEXT I
2460 WAIT 1
2470 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(2)
2480 WAIT 3
2490 OUTPUT @Gpio_14 USING "#,W";0
2500 WAIT 4
2510 OUTPUT @Gpio_12 USING "#,W";0
2520 GOSUB Safe_tester
2530 GOSUB Reset_ir
2540 ON KBD GOTO Time_again
2550 DISP "DO YOU NEED TO MAKE THIS MEASUREMENT AGAIN (Y/N)?"
2560 Wait2:GOTO Wait2
2570 Time_again:      !
2580 T$=KBD$
2590 IF T$="Y" THEN Verify_timing
2600 IF T$<>"N" THEN 2540
2610 Label$=""
2620 Disp1$="(CP21) RECORD THIS READING (FROM THE 50% POINTS) AS THE TIME INTER
        VAL"
2630 Disp2$="IT SHALL BE BETWEEN 2 AND 9 SECONDS"
2640 Disp3$="REMOVE CALIBRATION EQUIPMENT AND CLOSE CAL. DOOR"
2650 GOSUB Wait_for_key
2660 !*****
2670 Simulator_ck:    IVERIFYS SIMULATORS
2680 PRINT CHR$(12)
2690 Continuity_sim:  !
2700 !
2710 R_up(1)=1.0002 ! REPRESENTED BY x.xxxx
2720 R_low(1)=1.0001 ! REPRESENTED BY y.yyyy

```

```

2730 R_up(2)=1.0002 ! REPRESENTED BY x.xxxx
2740 R_low(2)=1.0001 ! REPRESENTED BY y.yyyy
2750 R_up(3)=1.0002 ! REPRESENTED BY x.xxxx
2760 R_low(3)=1.0001 ! REPRESENTED BY y.yyyy
2770 PRINT CHR$(12)
2780 DISP ""
2790 Label$="VERIFYING CONTINUITY SIMULATOR"
2800 Disp1$="          PLACE CONTINUITY SIMULATOR IN CONTINUITY SIDE OF FIXTURE"
2810 Disp2$=""
2820 Disp3$=""
2830 GOSUB Wait_for_key
2840 GOSUB Door_open
2850 GOSUB Arm_tester
2860 PRINT CHR$(12)
2870 !
2880 Cont_1:OUTPUT @Gpio_12 USING "#,W";2^1+2^3
2890 OUTPUT @Keithley;"R0P0Z0T5G1X"
2900 PRINT CHR$(12)
2910 CONTROL CRT;25,15
2920 PRINT "TESTING SIMULATOR"
2930 CONTROL CRT;22,17
2940 PRINT "CONTINUITY TEST NUMBER 1"
2950 WAIT 1
2960 ENTER @Keithley;R$(1)
2970 R(1)=VAL(R$(1))
2980 R(1)=INT(R(1)*10^4)/10^4 !IMPLIED ZERO
2990 R$(1)=VAL$(R(1))
3000 IF Cont_test_num<>0 THEN Cont_end
3010 Cont_2:OUTPUT @Gpio_12 USING "#,W";2^1+2^2
3020 OUTPUT @Keithley;"R0P0Z0T5G1X"
3030 PRINT CHR$(12)
3040 CONTROL CRT;25,15
3050 PRINT "TESTING SIMULATOR"
3060 CONTROL CRT;22,17
3070 PRINT "CONTINUITY TEST NUMBER 2"
3080 WAIT 1
3090 ENTER @Keithley;R$(2)
3100 R(2)=VAL(R$(2))
3110 R(2)=INT(R(2)*10^4)/10^4 !IMPLIED ZERO
3120 R$(2)=VAL$(R(2))
3130 IF Cont_test_num<>0 THEN Cont_end
3140 Cont_3:OUTPUT @Gpio_12 USING "#,W";2^1+2^11
3150 OUTPUT @Keithley;"R0P0Z0T5G1X"
3160 PRINT CHR$(12)
3170 CONTROL CRT;25,15
3180 PRINT "TESTING SIMULATOR"
3190 CONTROL CRT;22,17
3200 PRINT "CONTINUITY TEST NUMBER 3"
3210 WAIT 1
3220 ENTER @Keithley;R$(3)
3230 R(3)=VAL(R$(3))
3240 R(3)=INT(R(3)*10^4)/10^4 !IMPLIED ZERO

```

```

3250 R$(3)=VAL$(R(3))
3260 Cont_end: !
3270 OUTPUT @Gpio_12 USING "#,W";0
3280 OUTPUT @Gpio_14 USING "#,W";0
3290 PRINT CHR$(12)
3300 !
3310 GOSUB Safe_tester
3320 PRINT CHR$(12)
3330 !
3340 PRINT TAB(11);"TEST";TAB(29);"LIMITS(OHMS)";TAB(45);"VALUE(ohms)";TAB(60);
"STATUS"
3350 PRINT
3360 FOR I=1 TO 3
3370     I$=VAL$(I)
3380     Cont_ar$(I)="ACCEPT"
3390     IF R_up(I)<R(I) THEN Cont_ar$(I)="REJECT"
3400     IF R_low(I)>R(I) THEN Cont_ar$(I)="REJECT"
3410     PRINT TAB(5);"CONT TEST NUMBER ";I$;TAB(27);R_up(I);TAB(35);R_low(I);TAB
(47);R$(I);TAB(60);Cont_ar$(I)
3420 NEXT I
3430 !
3440 ON KBD GOTO Cont_sim_again
3450 DISP "DO YOU NEED TO RUN THE CONTINUITY SIMULATOR AGAIN(Y/N)?"
3460 Wait1:GOTO Wait1
3470 Cont_sim_again:      !
3480 Cs$=KBD$
3490 IF Cs$="Y" THEN Continuity_sim
3500 IF Cs$<>"N" THEN 3440
3510 Ir_sim_ck:          !
3520 Ck_test=1
3530 Ck_test$="1"
3540 Sw_pos$="1"
3550 GOSUB Ck_accept
3560 Ck_test=8
3570 Ck_test$="8"
3580 Sw_pos$="2"
3590 GOSUB Ck_accept
3600 Ck_test=9
3610 Ck_test$="9"
3620 Sw_pos$="3"
3630 GOSUB Ck_accept
3640 Ck_test=2
3650 Ck_test$="2"
3660 Sw_pos$="4"
3670 GOSUB Ck_accept
3680 Ck_test=3
3690 Ck_test$="3"
3700 Sw_pos$="5"
3710 GOSUB Ck_accept
3720 Ck_test=5
3730 Ck_test$="5"
3740 Sw_pos$="6"

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3750 GOSUB Ck_accept
3760 Ck_test=6
3770 Ck_test$="6"
3780 Sw_pos$="7"
3790 GOSUB Ck_accept
3800 Ck_test=4
3810 Ck_test$="4"
3820 Sw_pos$="8"
3830 GOSUB Ck_accept
3840 Ck_test=7
3850 Ck_test$="7"
3860 Sw_pos$="8"
3870 GOSUB Ck_accept
3880 GOTO Post_cal
3890 Ck_accept:
3900 PRINT CHR$(12)
3910 Label$=""
3920 Disp1$="VERIFYING INSUL. RES. SIMULATOR TEST "&Ck_test$
3930 Disp2$="ON I.R. SIMULATOR BOX, MOVE SWITCHES TO POSITION "&Sw_pos$&" AND A
CCEPT"
3940 Disp3$=""
3950 GOSUB Wait_for_key
3960 GOSUB Arm_tester
3970 PRINT CHR$(12)
3980 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(Ck_test)
3990 OUTPUT @Gpio_14 USING "#,W";Volt_to_uut_14(Ck_test)
4000 IF Ck_test=1 THEN
4010     OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(Ck_test)+2^13+2^9
4020 ELSE
4030     OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(Ck_test)+2^13
4040 END IF
4050 ENTER @Gpio_14 USING "#,W";Monitor
4060 IF NOT BIT(Monitor,Comparator_mon) THEN Sim_fail
4070 WAIT 2
4080 ENTER @Gpio_14 USING "#,W";Monitor
4090 IF NOT BIT(Monitor,Comparator_mon) THEN Sim_fail
4100 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(Ck_test)!TURNS OFF VOLT TO HIGH
VOLT P.S.
4110 WAIT 3
4120 OUTPUT @Gpio_14 USING "#,W";0
4130 WAIT 4
4140 OUTPUT @Gpio_12 USING "#,W";0
4150 ENTER @Gpio_14 USING "#,W";Monitor
4160 IF NOT BIT(Monitor,Comparator_mon) THEN Sim_fail
4170 GOSUB Safe_tester
4180 !
4190 Ck_reject: !
4200 PRINT CHR$(12)
4210 Label$=""
4220 Disp1$="VERIFYING INSUL. RES. SIMULATOR TEST "&Ck_test$
4230 Disp2$="ON INSUL. R. SIMULATOR BOX, MOVE SWITCHES TO POSITION "&Sw_pos$&"
AND REJECT"

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4240 Disp3$=""
4250 GOSUB Wait_for_key
4260 GOSUB Arm_tester
4270 PRINT CHR$(12)
4280 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(Ck_test)
4290 OUTPUT @Gpio_14 USING "#,W";Volt_to_uut_14(Ck_test)
4300 IF Ck_test=1 THEN
4310     OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(Ck_test)+2^13+2^9
4320 ELSE
4330     OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(Ck_test)+2^13
4340 END IF
4350 WAIT 2
4360 OUTPUT @Gpio_12 USING "#,W";Volt_to_uut_12(Ck_test)!TURNS OFF VOLT TO HIGH
    VOLT P.S.
4370 ENTER @Gpio_14 USING "#,W";Monitor    !CHECKS STATE OF COMPARATOR
4380 IF BIT(Monitor,Comparator_mon) THEN Sim_fail
4390 WAIT 3
4400 OUTPUT @Gpio_14 USING "#,W";0
4410 WAIT 4
4420 OUTPUT @Gpio_12 USING "#,W";0
4430 ENTER @Gpio_14 USING "#,W";Monitor    !CHECKS STATE COMPARATOR
4440 IF BIT(Monitor,Comparator_mon) THEN Sim_fail
4450 PRINT CHR$(12)
4460 GOSUB Safe_tester
4470 GOSUB Reset_ir
4480 RETURN
4490 !*****
4500 Sim_fail: ! INFORMS OF SIMULATOR FAILURE ON I.R. TESTING
4510 PRINT CHR$(12)
4520 CONTROL CRT;25,15
4530 PRINT "***** SIMULATOR FAILURE *****"
4540 BEEP 500,.5
4550 WAIT .5
4560 BEEP 500,.5
4570 PRINT CHR$(12)
4580 GOSUB Safe_tester
4590 GOSUB Reset_ir
4600 PRINT CHR$(12)
4610 MOVE 22,70
4620 PRINT TABXY(8,10);"SIMULATOR FAILURE.  CHECK SWITCH POSITIONS ON SIMULATOR
    BOX"
4630 PRINT TABXY(8,11);Disp2$
4640 ON KBD GOTO Ck_again
4650 DISP "DO YOU NEED TO CHECK THIS POSITION AGAIN (Y/N)?"
4660 Wait5:GOTO Wait5
4670 Ck_again:Ck$=KBD$
4680 IF Ck$="Y" THEN
4690     IF Disp2$[61,66]="REJECT" THEN
4700         GOTO Ck_reject
4710     ELSE
4720         GOTO Ck_accept
4730     END IF

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4740 END IF
4750 IF Ck$<>"N" THEN Wait5
4760 PRINT CHR$(12)
4770 DISP ""
4780 CONTROL CRT;20,18
4790 PRINT "NOTIFY MAINTENANCE"
4800 GOTO End
4810 !*****
4820 Door_open: ! MAKES SURE SAFETY CHAMBER DOOR IS CLOSED
4830 ENTER @Gpio_14 USING "#,W";Monitor
4840 IF BIT(Monitor,Door_mon)=1 THEN
4850     CONTROL CRT;25,15
4860     PRINT CHR$(130);"***** CLOSE CHAMBER DOOR *****";CHR$(128)
4870     WAIT 3
4880     GOTO Door_open
4890 END IF
4900 PRINT CHR$(12)
4910 RETURN
4920 !*****
4930 Safe_tester:! MAKES SURE KEY IS IN SAFE POSITION
4940 ENTER @Gpio_14 USING "#,W";Monitor
4950 IF BIT(Monitor,Key_mon)=0 THEN
4960     DISP ""
4970     CONTROL CRT;25,15
4980     PRINT CHR$(130);"***** SAFE TESTER *****";CHR$(128)
4990     WAIT 3
5000     GOTO Safe_tester
5010 END IF
5020 PRINT CHR$(12)
5030 RETURN
5040 !*****
5050 Arm_tester:! MAKES SURE KEY IS IN ARMED POSITION
5060 ENTER @Gpio_14 USING "#,W";Monitor
5070 IF BIT(Monitor,Key_mon)=1 THEN
5080     CONTROL CRT;25,15
5090     PRINT CHR$(130);"***** ARM TESTER *****";CHR$(128)
5100     WAIT 3
5110     GOTO Arm_tester
5120 END IF
5130 RETURN
5140 !*****
5150 Reset_ir:! INSTRUCTS TO RESET INSULATION RESISTANCE BUTTON
5160 ENTER @Gpio_14 USING "#,W";Monitor
5170 IF BIT(Monitor,Comparator_mon)=0 THEN
5180     CONTROL CRT;20,15
5190     PRINT CHR$(130);"***** RESET I.R. BUTTON *****";CHR$(128)
5200     WAIT 3
5210     GOTO Reset_ir
5220 END IF
5230 RETURN
5240 !*****
5250 Wait_for_key: !*****

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5260 ON KBD GOTO Exit1
5270 MOVE 22,70
5280 CSIZE 8,.4
5290 LABEL Label$
5300 PRINT TABXY(8,10);Disp1$
5310 PRINT TABXY(8,11);Disp2$
5320 PRINT TABXY(8,12);Disp3$
5330 Wait_loop1:DISP "Press ANY KEY when ready."
5340 WAIT .25
5350 DISP
5360 WAIT .25
5370 GOTO Wait_loop1
5380 Exit1:OFF KBD
5390 DISP
5400 CONTROL 1;1,18
5410 PRINT USING "50X"
5420 OFF ERROR
5430 PRINT CHR$(12)
5440 DISP ""
5450 RETURN
5460 !
5470 Post_cal:!
5480 PRINT TABXY(15,9);"CONTINUE WITH SECTION 3.10 OF CALIBRATION PROCEDURE"
5490 End:END
```

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R008764819